

# PHILIPS

sense and simplicity

## The Status of the Digital

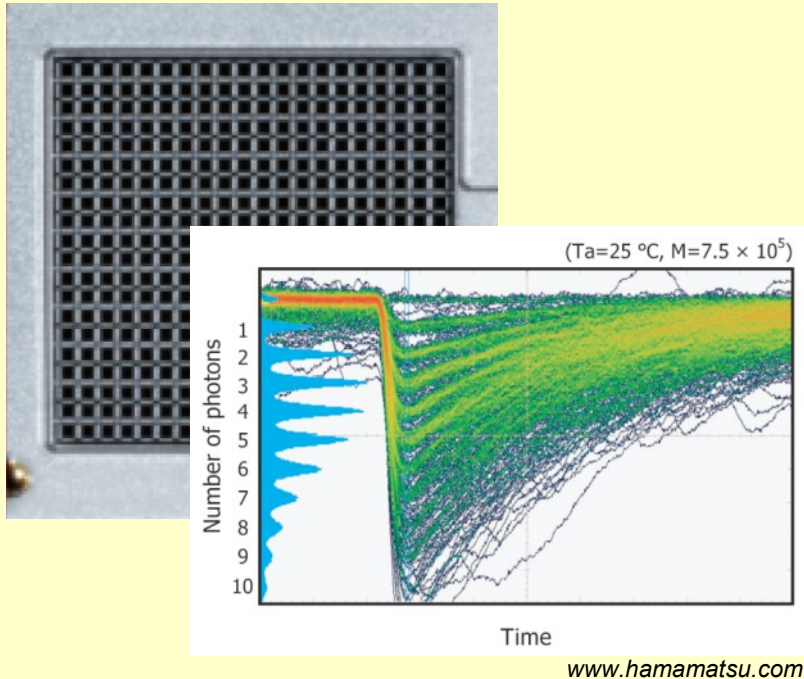
## Silicon Photomultiplier Development

Thomas Frach, Andreas Thon, Ben Zwaans, Carsten Degenhardt, Rik de Gruyter,  
Oliver Mühlens

Philips Digital Photon Counting

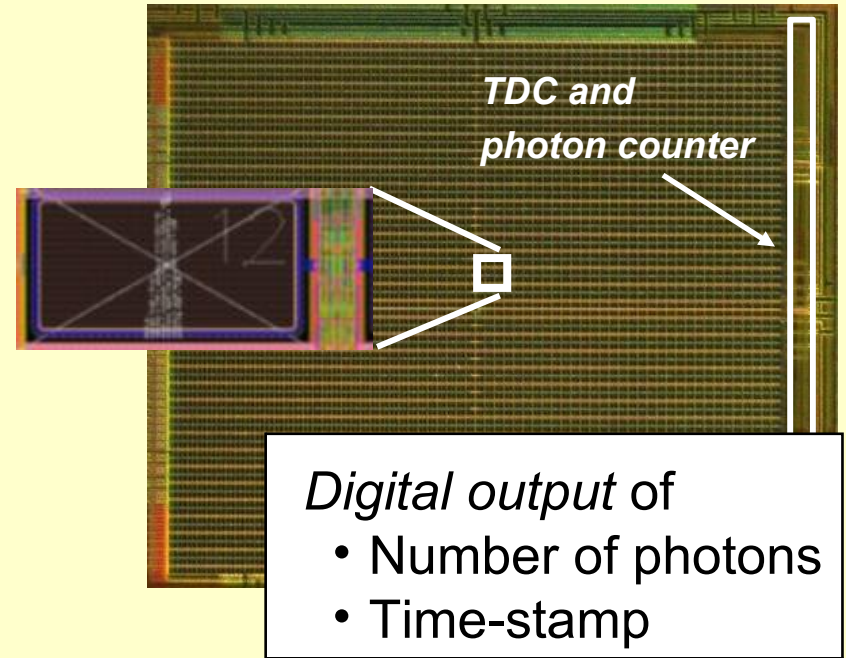
# Digital SiPM – New Type of Silicon Photomultiplier

## Analog SiPM



- Cells connected to common readout
- Analog sum of charge pulses
- Analog output signal

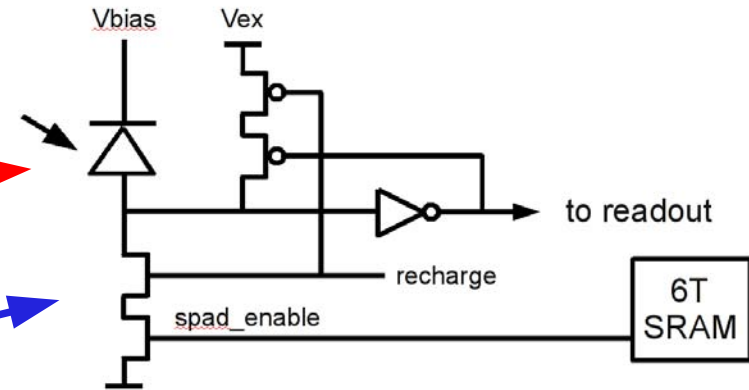
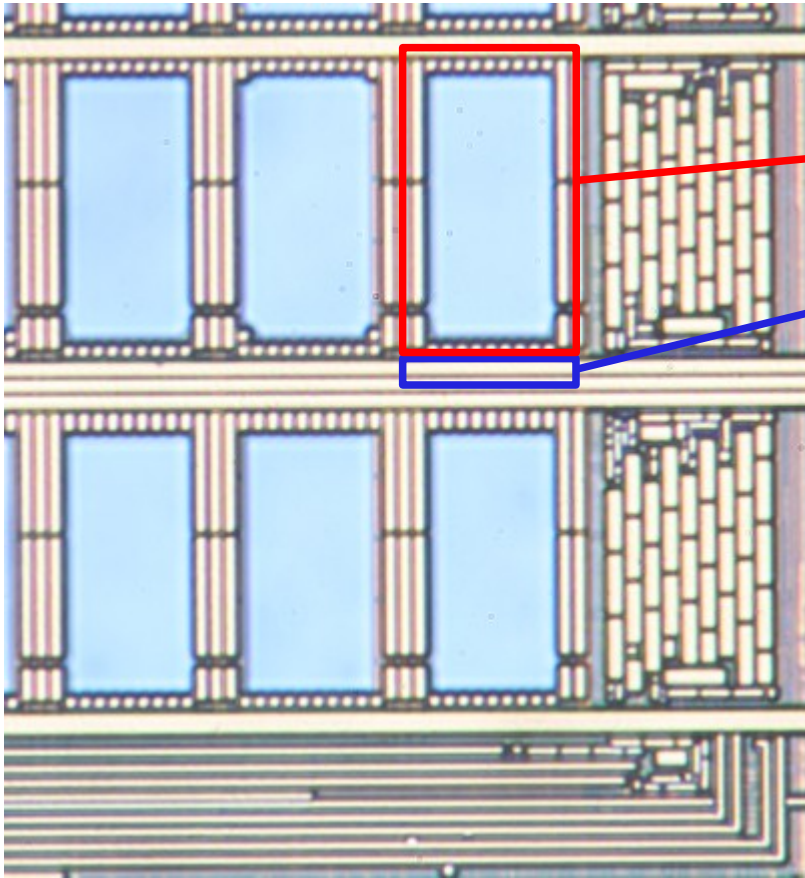
## Digital SiPM



- Digital output of*
- Number of photons
  - Time-stamp

- Each diode is a digital switch
- Digital sum of detected photons
- Digital data output

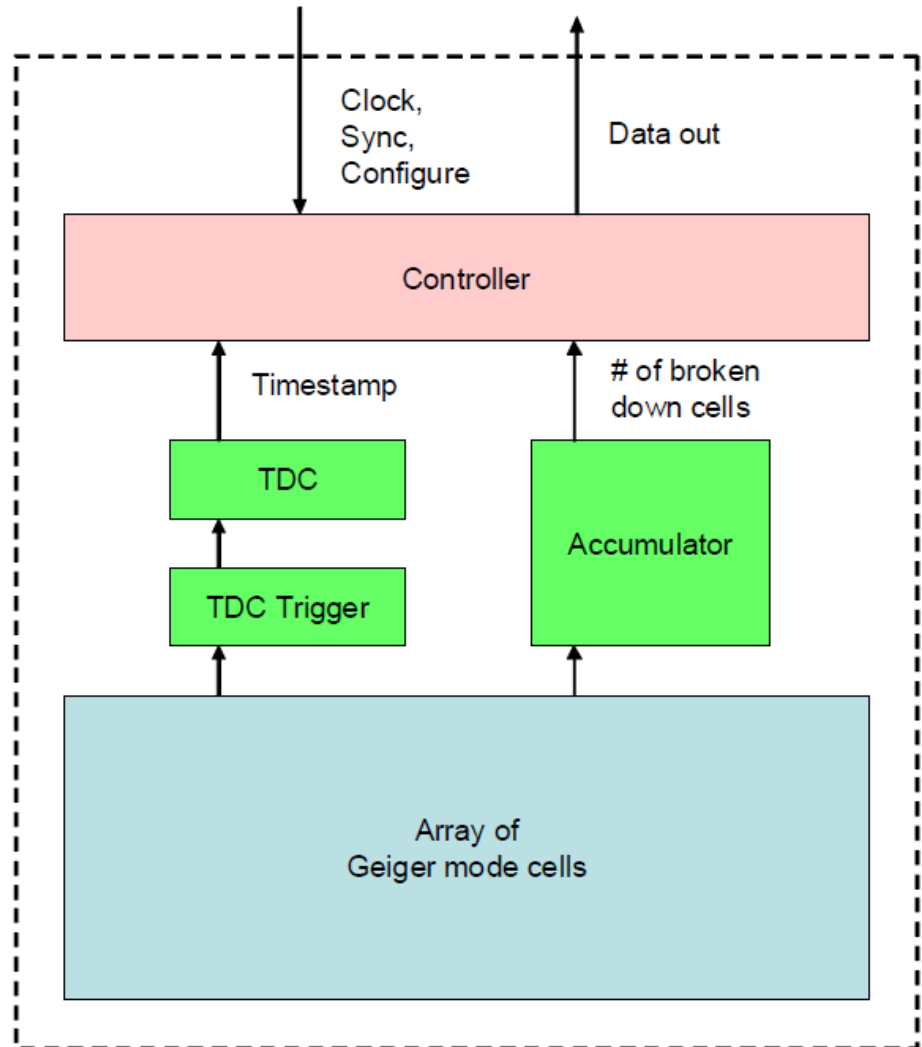
# Digital SiPM – Cell Electronics



- Cell electronics area:  $120\mu\text{m}^2$
- 25 transistors including 6T SRAM
- ~6% of total cell area
- Modified  $0.18\mu\text{m}$  5M CMOS
- Foundry: NXP Nijmegen

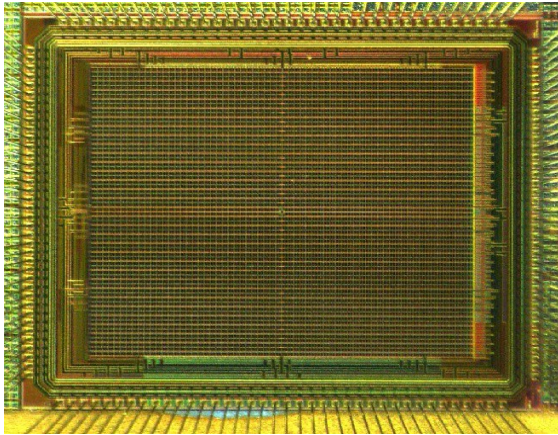
# Digital SiPM – Sensor Architecture

- Operating frequency: 200MHz
- 9bit TDC (23ps bin width)
- Configurable trigger network
- Validation logic to reduce sensor dead time due to dark counts
- JTAG interface
- Electrical trigger input for test and TDC calibration



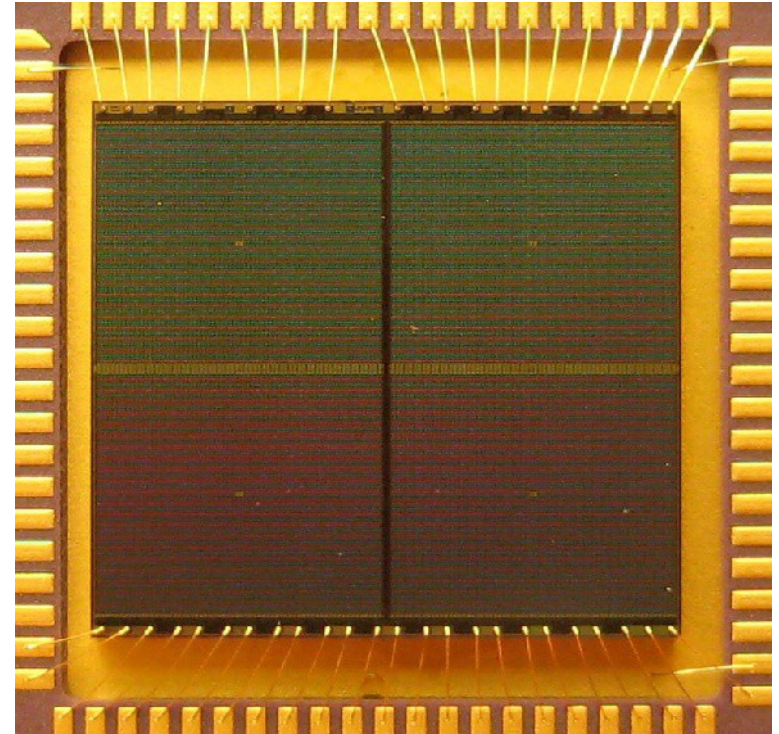
# Digital SiPM – Sensor Family

DLD8K Demonstrator (2009):



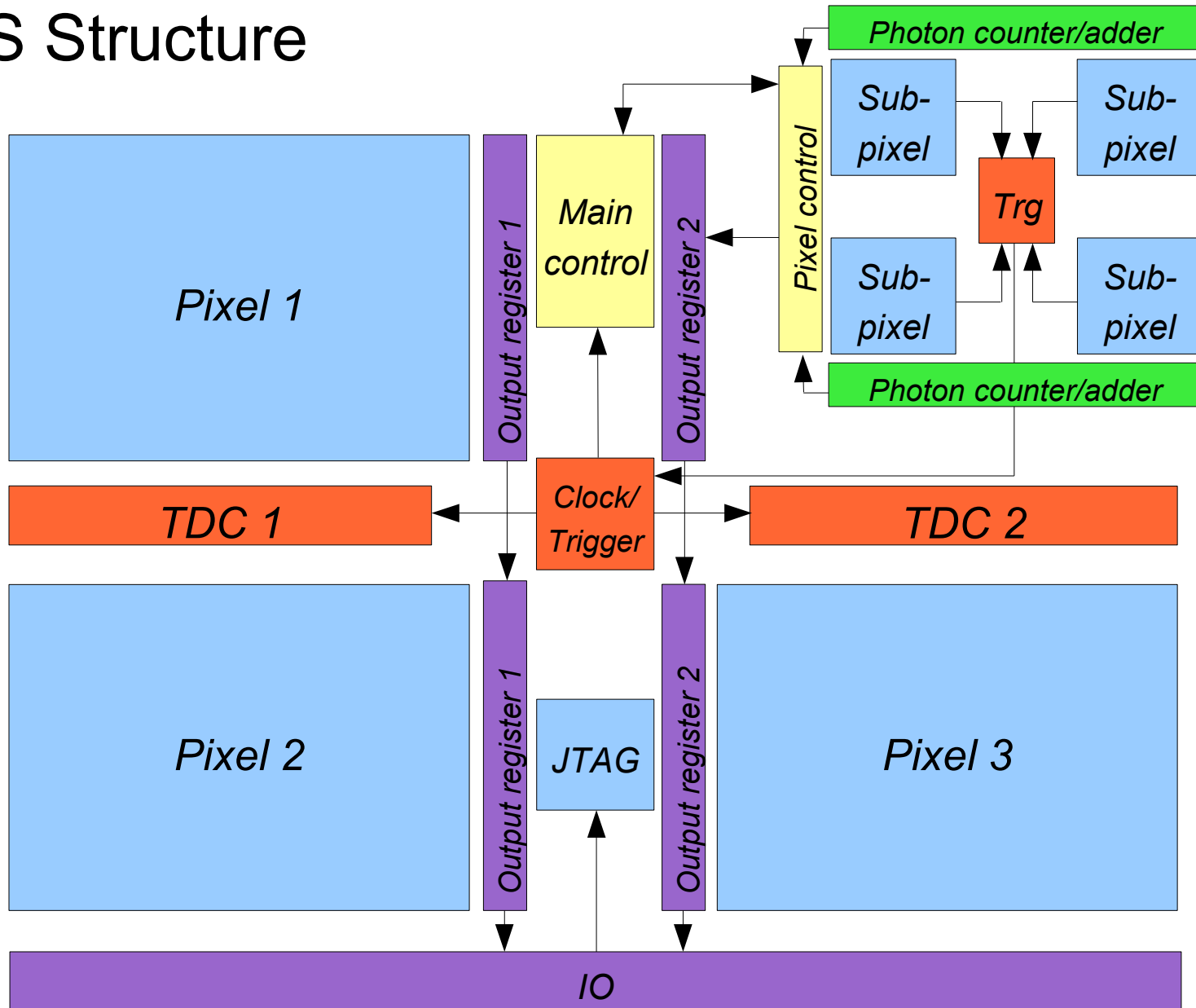
- 8192 cells
- Integrated TDC
- On-chip inhibit memory controller
- External FPGA controller
- 160 bond wires

DLS 6400-22 digital SiPM (2010):

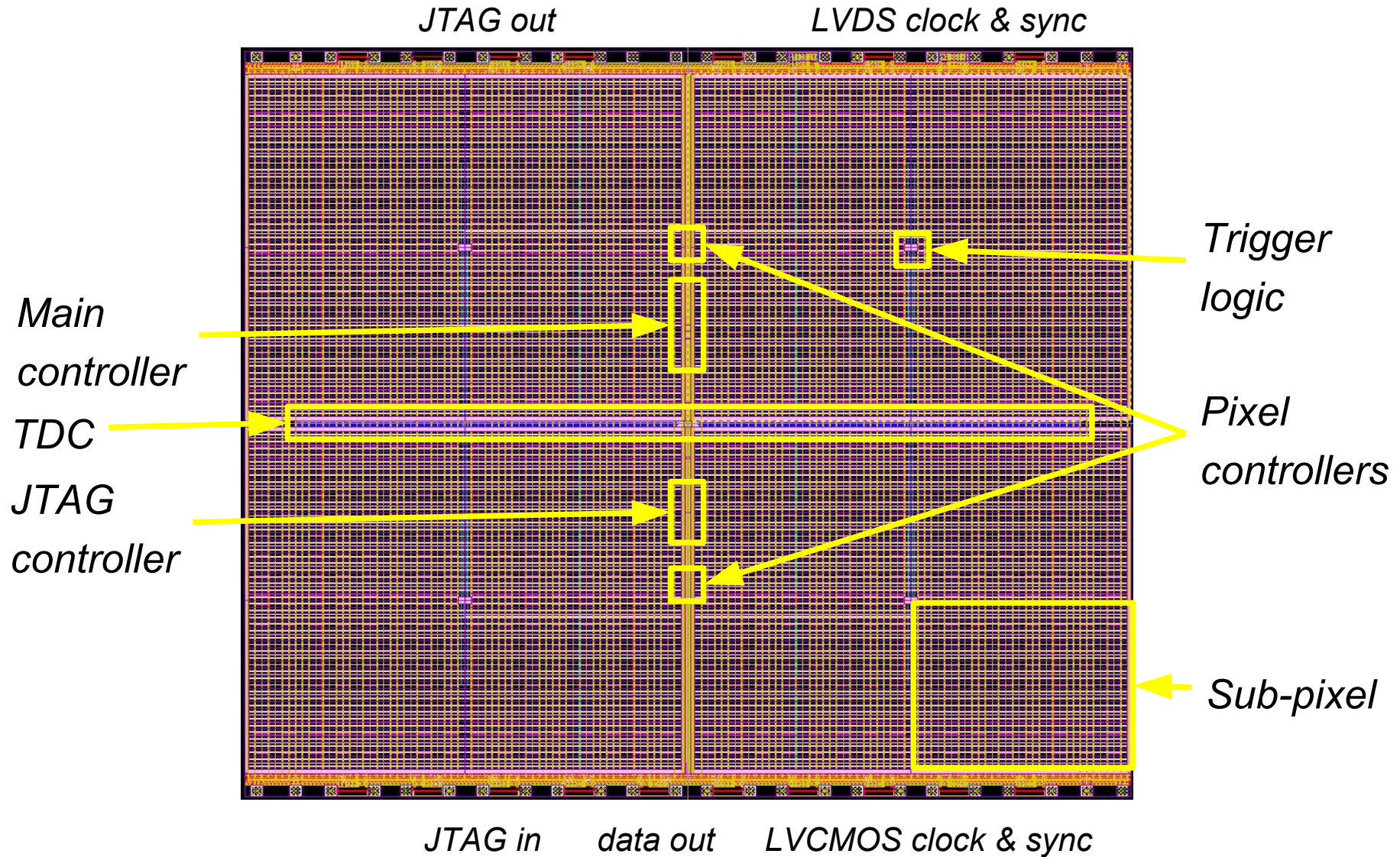


- 25600 cells
- TDCs, controller, data buffers
- JTAG for configuration & test
- 48 bond wires

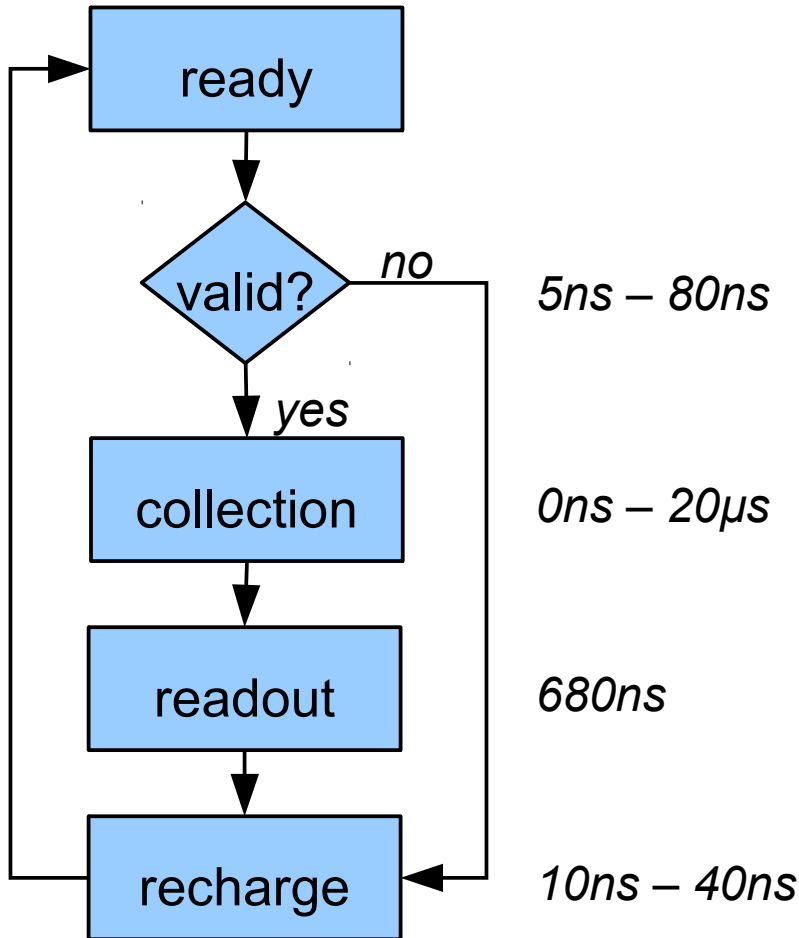
# DLS Structure



# DLS – Sensor Architecture



# DLS – State Machine

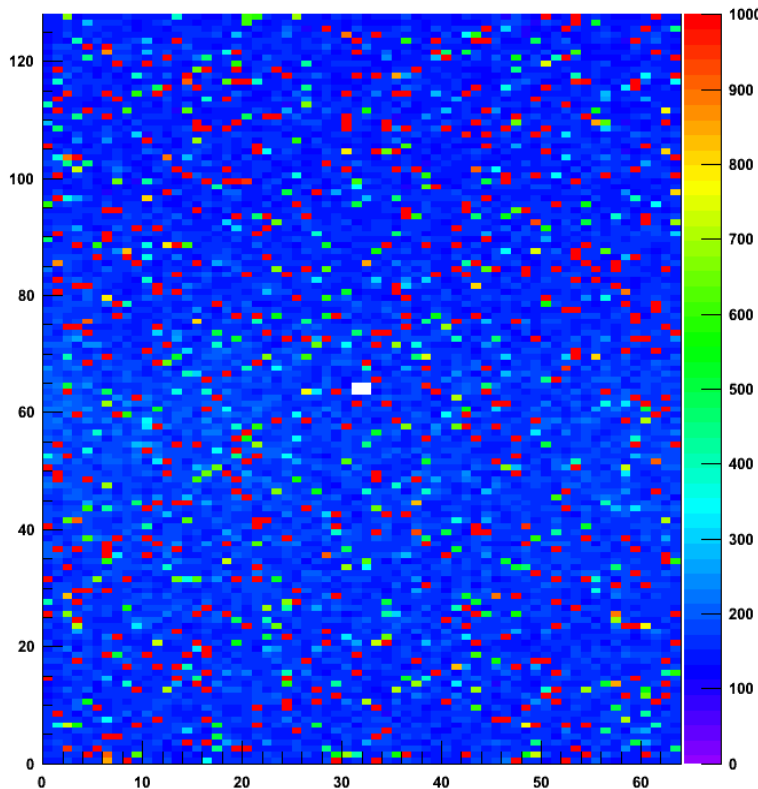


- 200MHz (5ns) system clock
- Variable light collection time 0 - 20μs
- 20ns min. dark count recovery
- dark counts => sensor dead-time
- data output parallel to the acquisition of the next event (no dead time)
- Trigger at 1, ≥2, ≥3 and ≥4 photons
- Validate at ≥4 ... ≥64 photons  
(possible to bypass event validation)

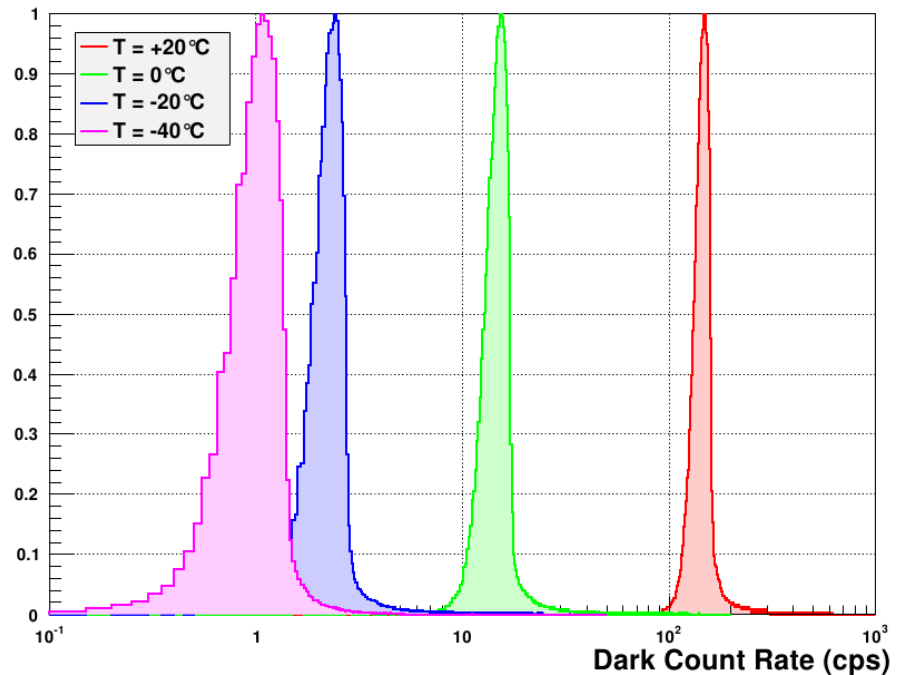


# DLD8K – Dark Counts

Control over individual SPADs enables detailed device characterization

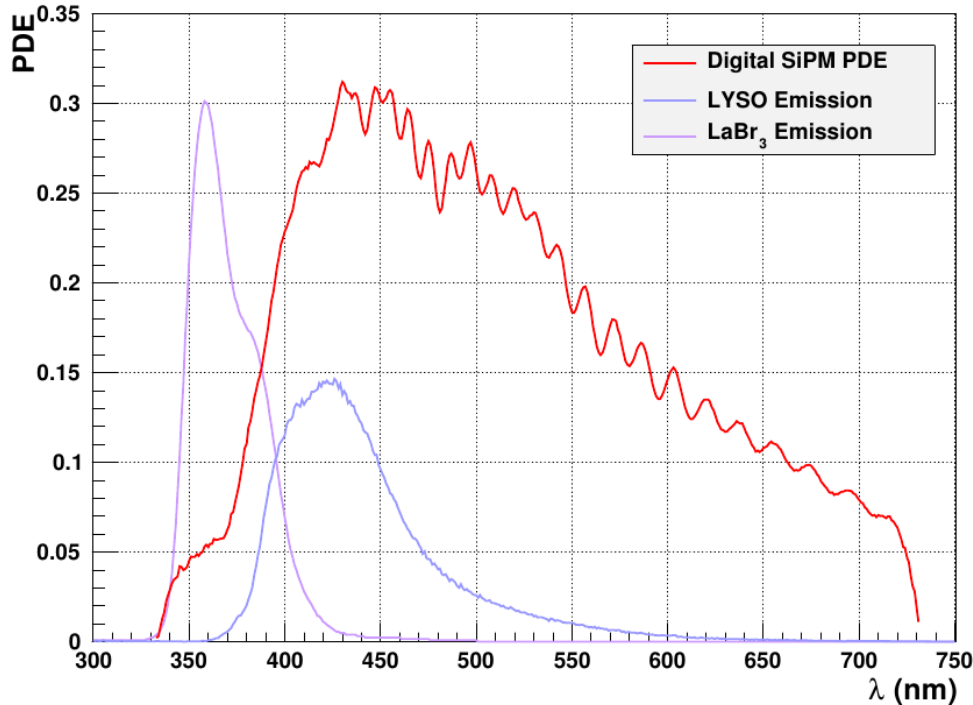


SPAD Dark Count Rate Distribution



- Over 90% good diodes (dark count rate close to average)
- Typical dark count rate at 20°C and 3.3V excess voltage: ~150cps / diode
- Low dark counts (~1-2cps) per diode at -40°C

# DLD8K – Photon Detection Efficiency



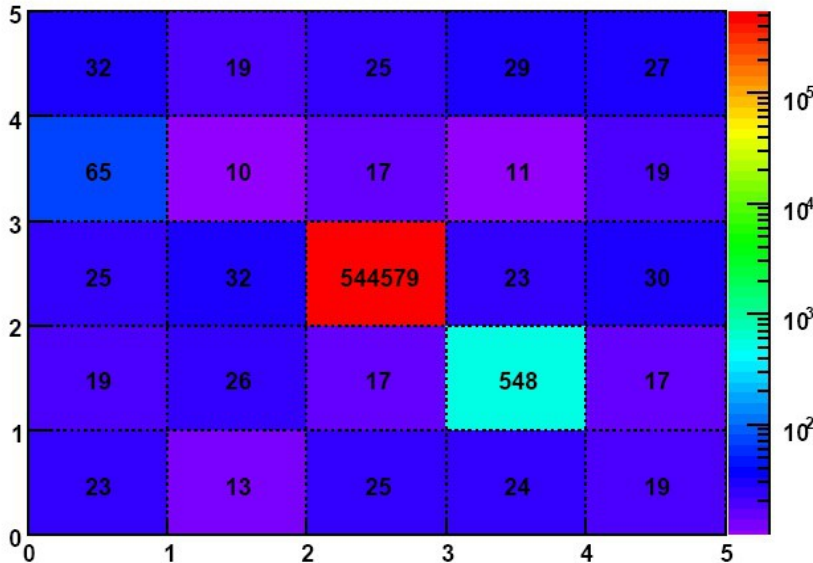
Effective PDE:

LYSO(Ce)	25.9%
CsI(Na)	23.7%
CsI(Tl)	20.5%
NaI(Tl)	24.2%
BGO	24.2%
LaBr <sub>3</sub> (Ce)	9.6%

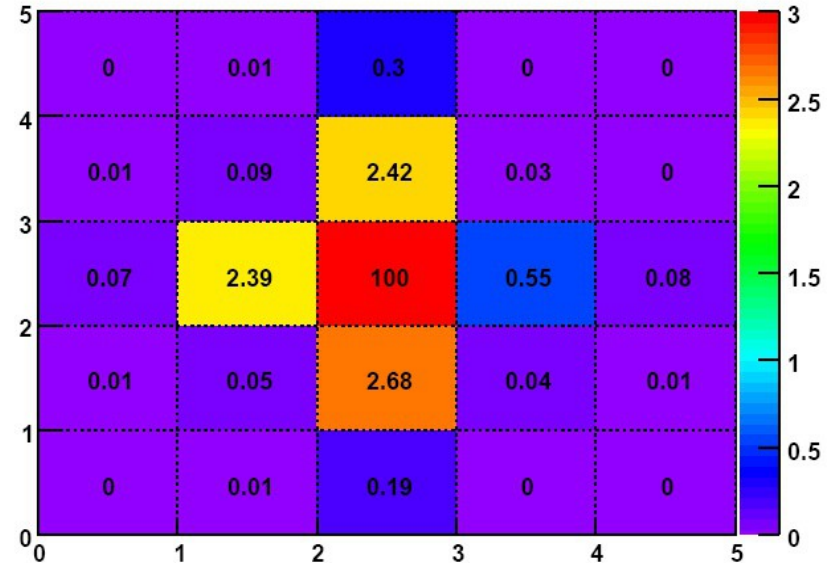
- Peak PDE >30% at 430nm and 3.3V excess voltage
- No anti-reflective coating used, optical coupling not optimized
- Needs independent verification

# DLD8K – Optical Crosstalk

Dark Count Rate [Hz]



Optical Crosstalk [%]



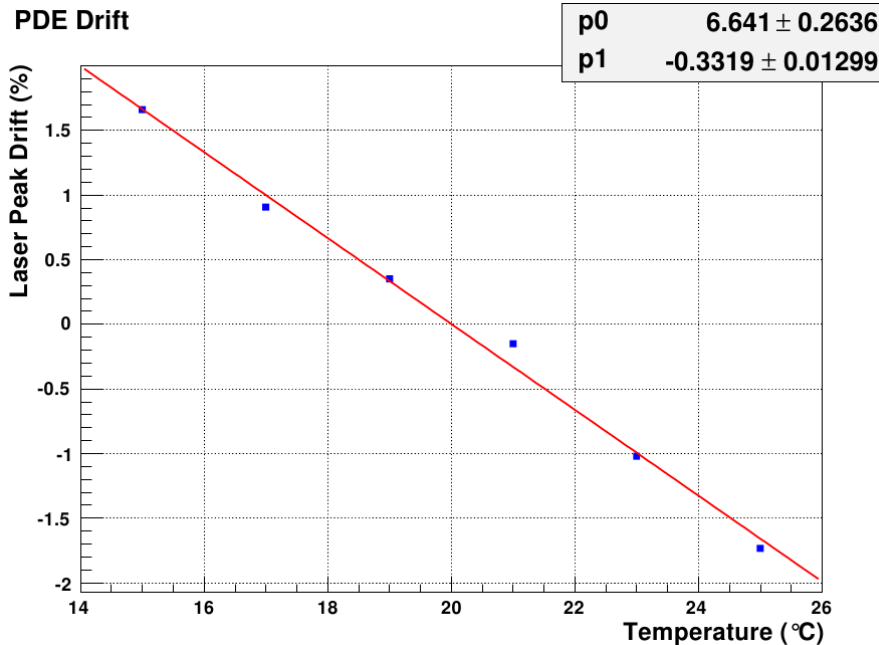
Direct measurement using one ,bad' diode as light generator:

- Acquire dark count map around the light source for corrections
- Activate light source **and** test diode simultaneously:
  - Events with 1 photon are dark counts
  - Events with 2 photons are either randoms or optical crosstalk
- Use the dark count map to correct for randoms

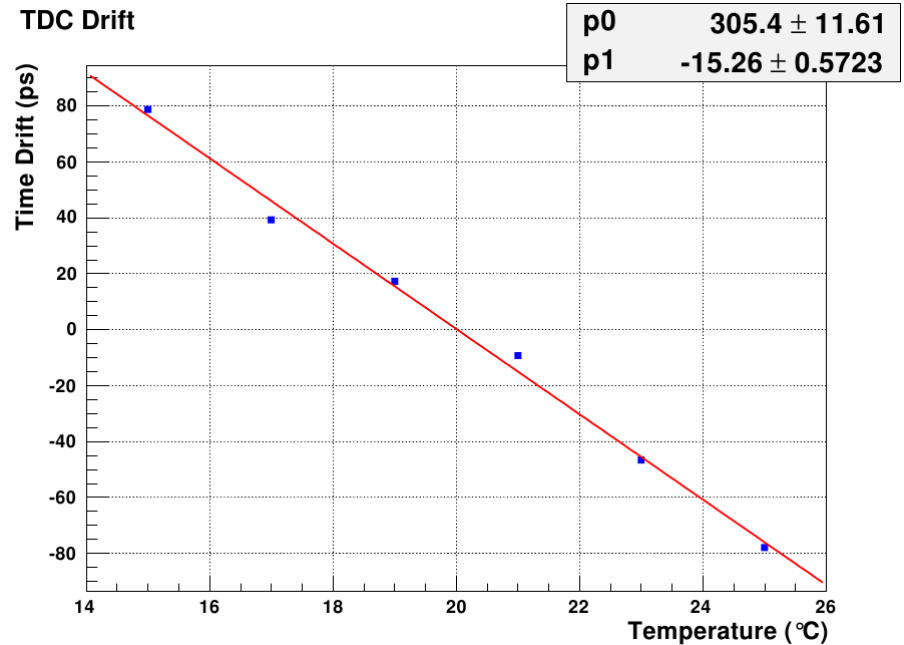
Typical total optical crosstalk in a 5x5 neighborhood: 7% - 9%

# DLD8K – Temperature Sensitivity

PDE Drift



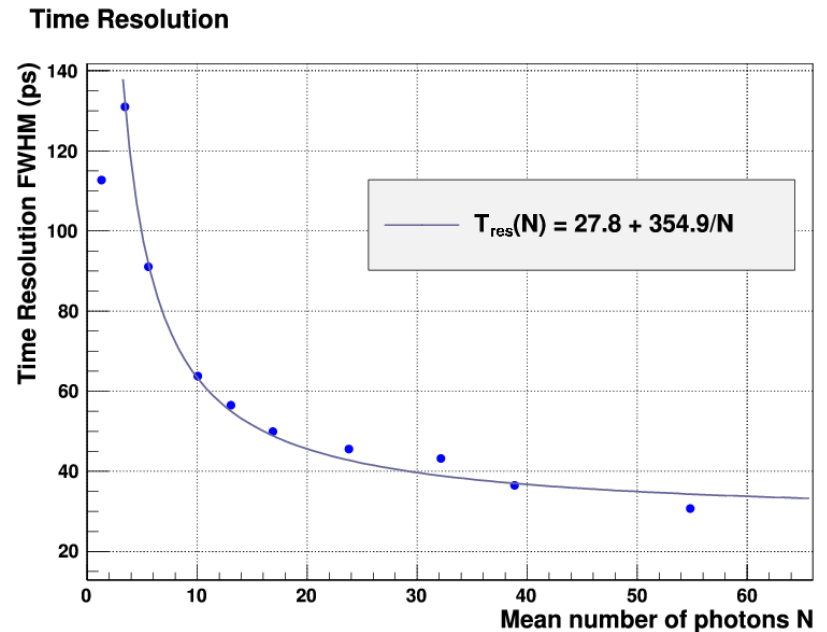
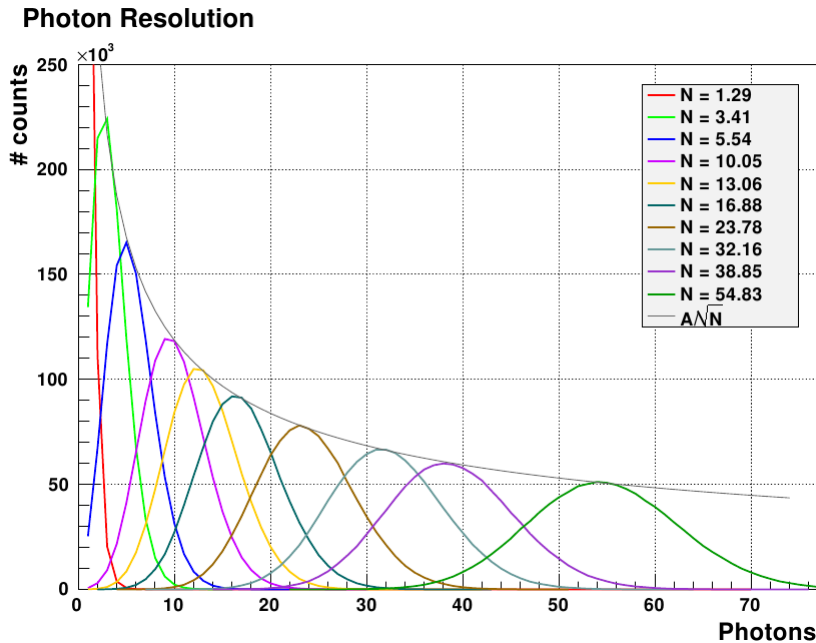
TDC Drift



ps-laser trigger, 2100 photons/pulse, 24ps FWHM timing resolution

- PDE drift:  $0.33\% \text{ K}^{-1}$
- TDC drift:  $15.3\text{ps K}^{-1}$
- PDE drift compensation by adapting the bias voltage
- TDC re-calibration using electrical trigger

# DLD8K – Photon And Time Resolution



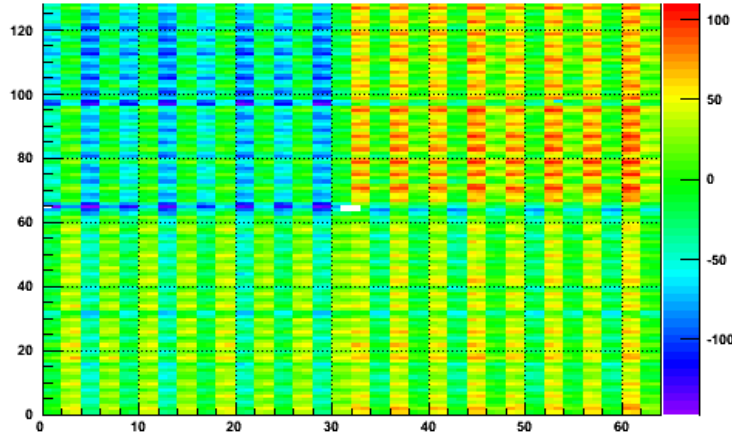
- Sensor triggered by attenuated laser pulses at first photon level
- Laser pulse width: 36ps FWHM,  $\lambda = 410\text{nm}$
- Contribution to time resolution (FWHM):

SPAD: 54ps, trigger network: 110ps, TDC: 20ps

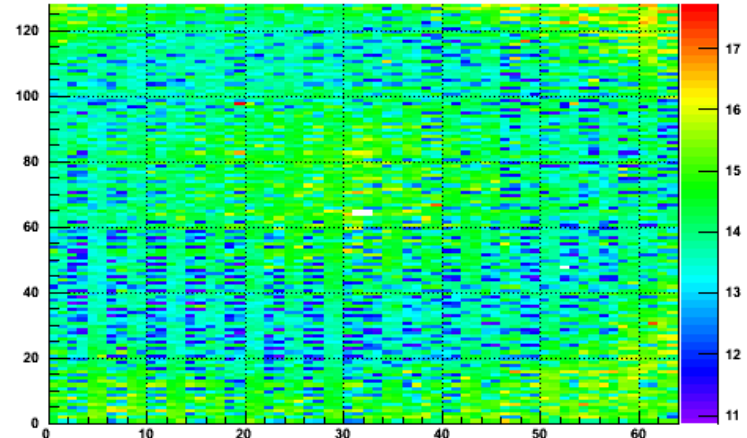
- Trigger network skew currently limits the timing resolution

# DLD8K – Trigger Network Skew

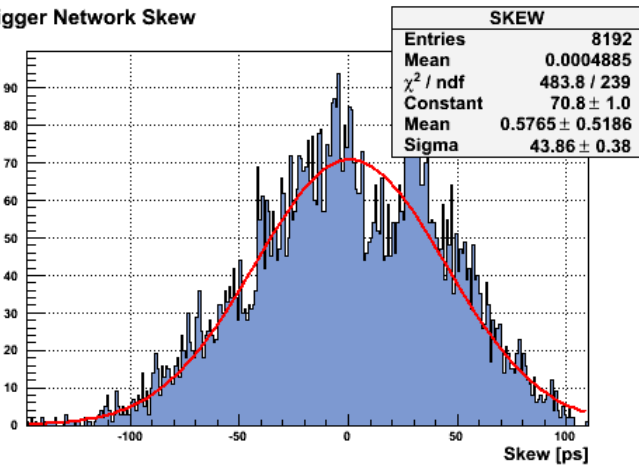
TDC Laser Map (Skew)



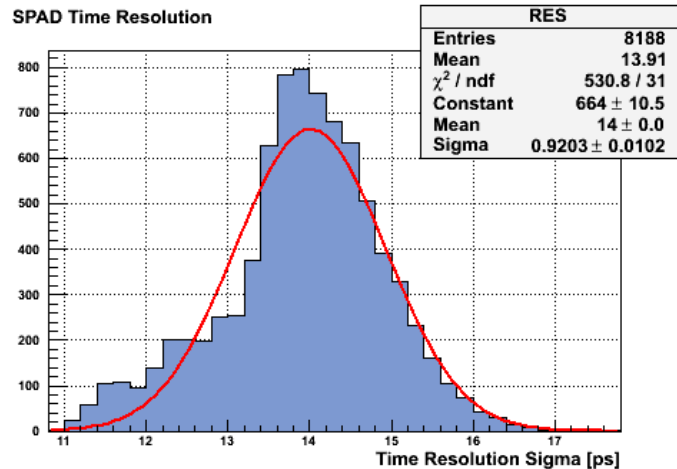
TDC Laser Map (Sigma)



Trigger Network Skew



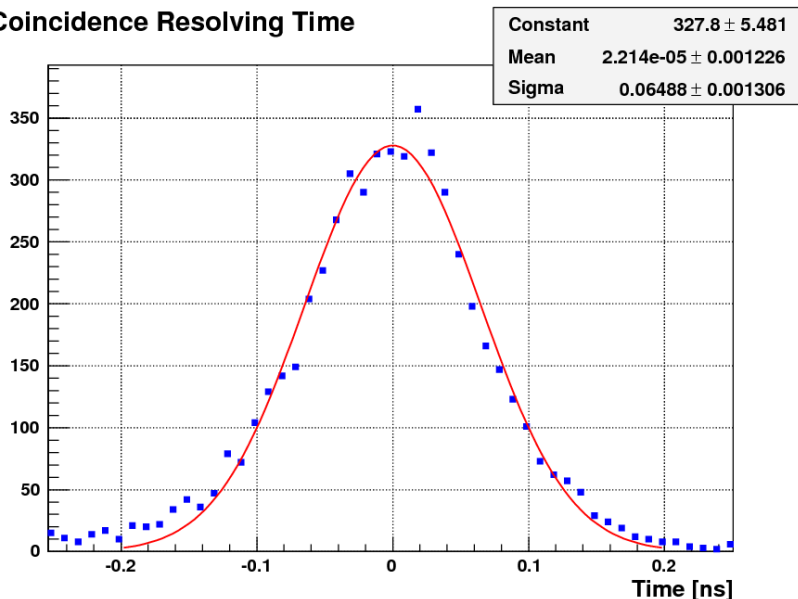
SPAD Time Resolution



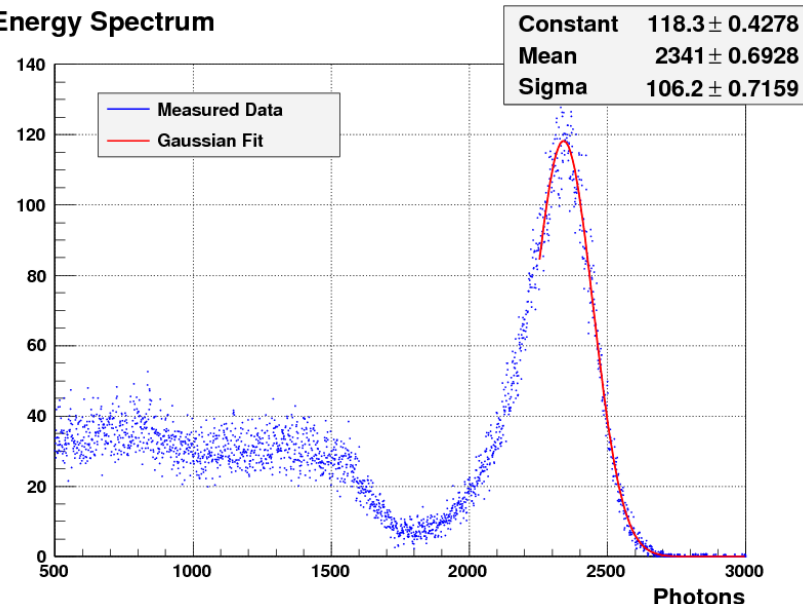
- Diodes activated one-by-one and triggered by a divergent ps-laser pulse.
- Many photons per diode&pulse → negligible avalanche spread uncertainty.
- Laser trigger&pulse spread and TDC resolutions are included in the final  $\sigma$ .

# DLD8K – Scintillator Measurements

Coincidence Resolving Time

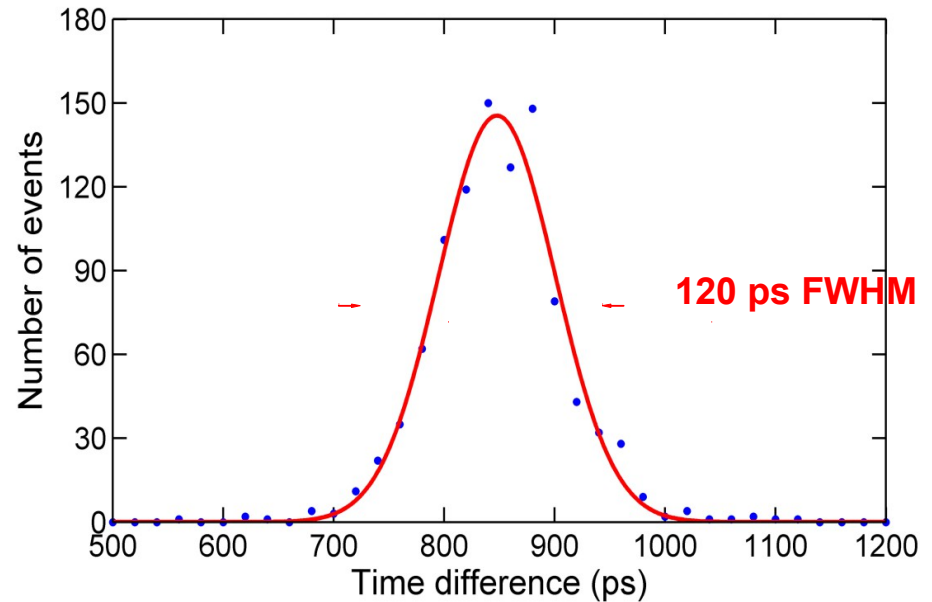
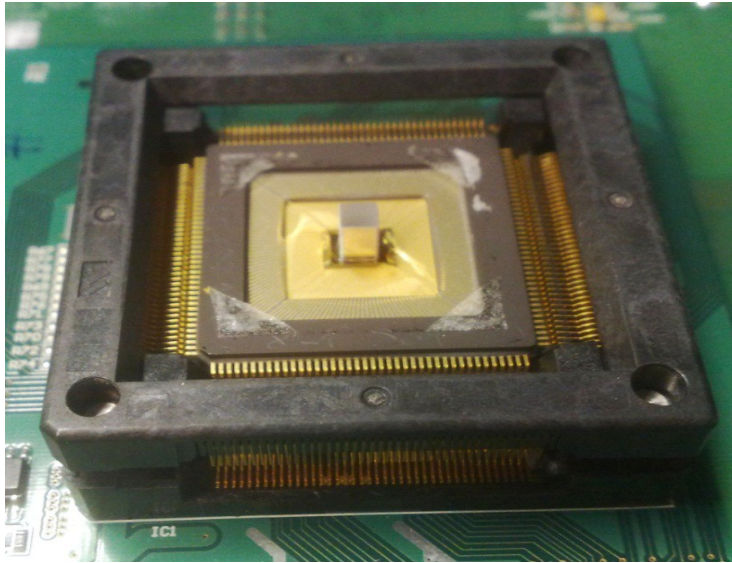


Energy Spectrum



- 3 x 3 x 5 mm<sup>3</sup> LYSO in coincidence, Na-22 source
- Time resolution in coincidence: **153ps** FWHM
- Energy resolution (excluding escape peak): **10.7%**
- Excess voltage 3.3V, 98.5% active cells
- Room temperature (31°C board temperature, not stabilized)

# DLD8K – Scintillator Measurements (II)

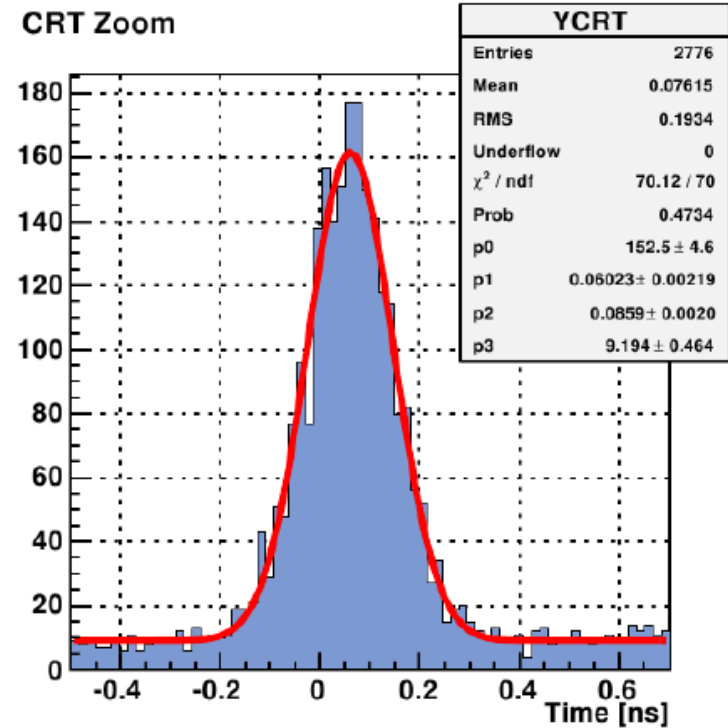
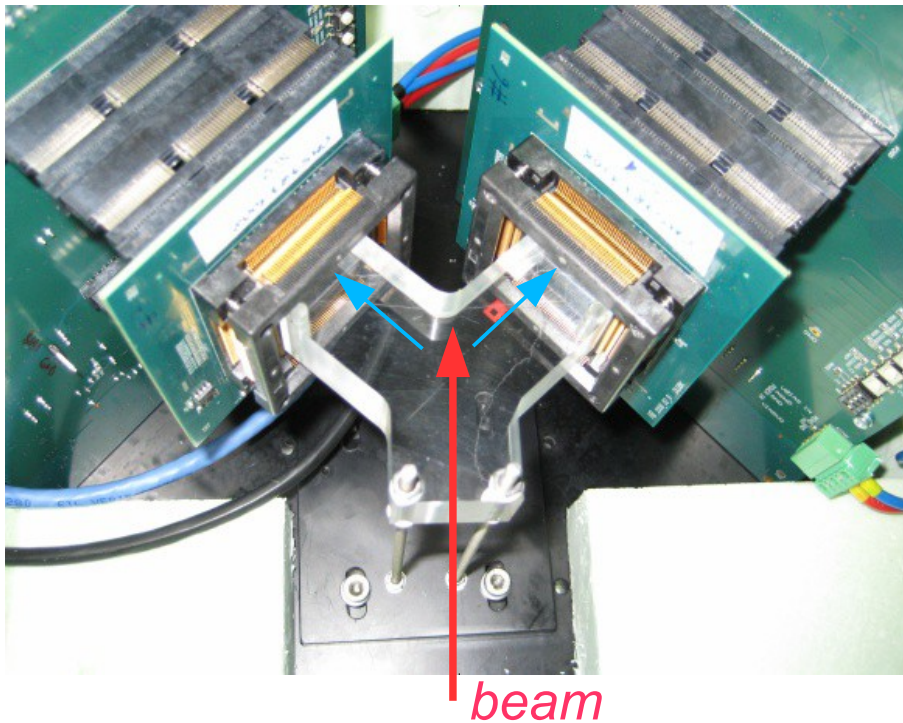


- 3 x 3 x 5 mm<sup>3</sup> Ca co-doped LSO:Ce in coincidence, Na-22 source
- Time resolution in coincidence: **120ps** FWHM
- Energy resolution: **10%**
- Room temperature

*D. R. Schaart, H. T. van Dam, G. J. van der Lei, S. Seifert,  
 "The Digital SiPM: Initial Evaluation of a New Photosensor for Time-of-Flight PET,"  
 2011 IEEE Nuclear Science Symposium and Medical Imaging Conference,  
 Valencia, Spain, October 23-29, 2011*

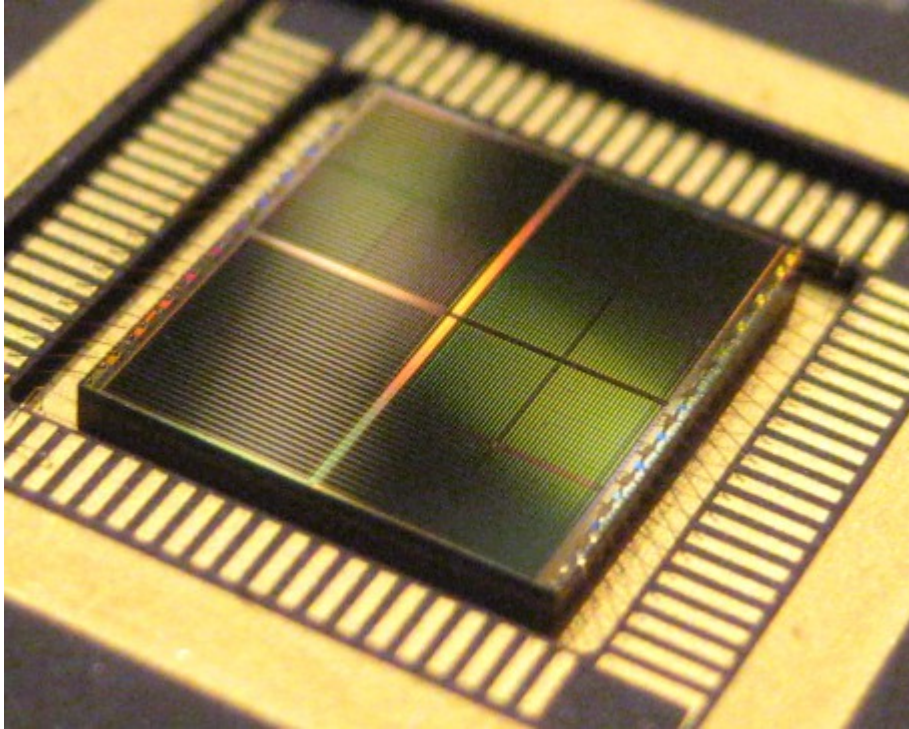


# DLD8K – Čerenkov Light Detection



- PMMA radiator coupled via air gap to two dSiPMs (DLD8K) in coincidence
- Box isolated and temperature-controlled with a TEC to 2 – 3°C
- Cooperation between Giessen University (Prof. Düren) and Philips DPC
- First measurements at CERN SPS:  $\sigma = 60.7\text{ps}$

# DLS 3200-22 (2011)

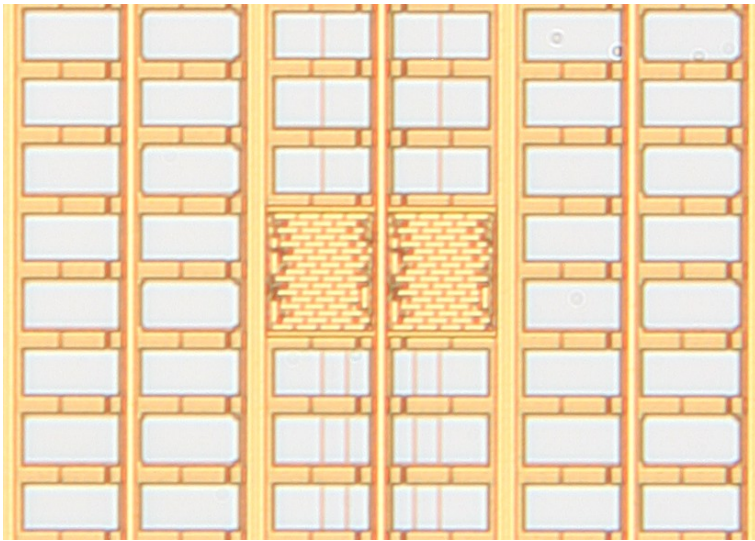


- Based on DLS 6400-22
- Fully compatible interface
- Two diode cells merged vertically resulting in  $59.4\mu\text{m} \times 64\mu\text{m}$  cell
- 3200 micro-cells per pixel
- Max. fill factor 84%
- Currently 78% (wide guard rings)
- Improved trigger network
- New trigger level scheme
- Modified validation scheme
- Improved event processing

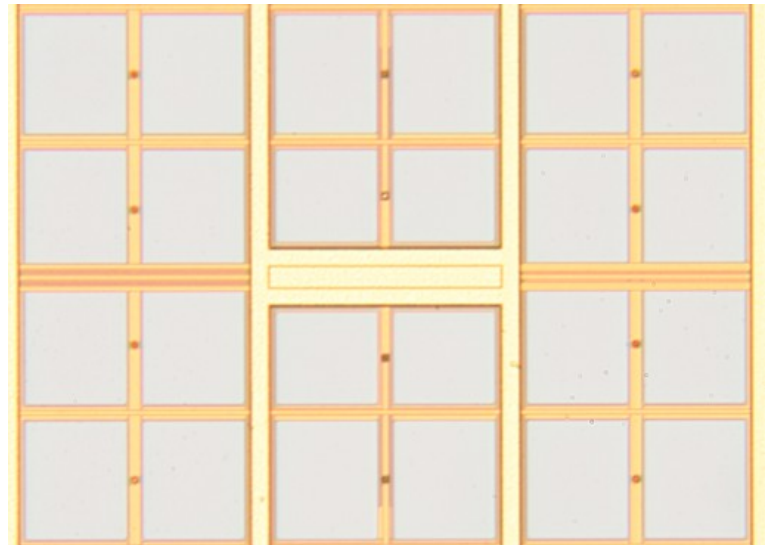
# DLS 3200-22 – Comparison

New Experimental Design DLS 3200-22:

- 3200 cells per pixel, 12800 cells per sensor
- 59.4 $\mu\text{m}$  x 64 $\mu\text{m}$  cell size, 78% area efficiency (incl. electronics)
- Based on (and compatible to) DLS 6400-22 sensor

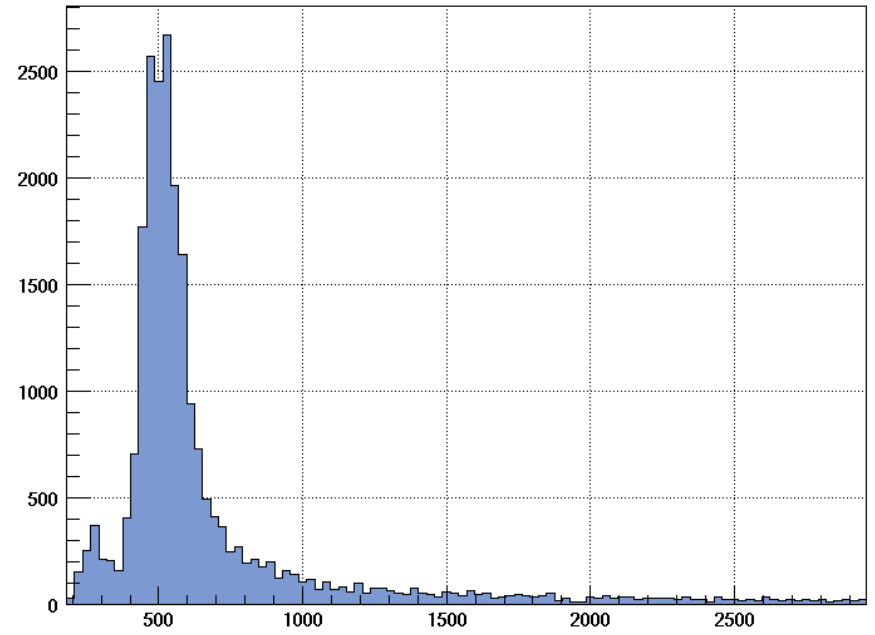
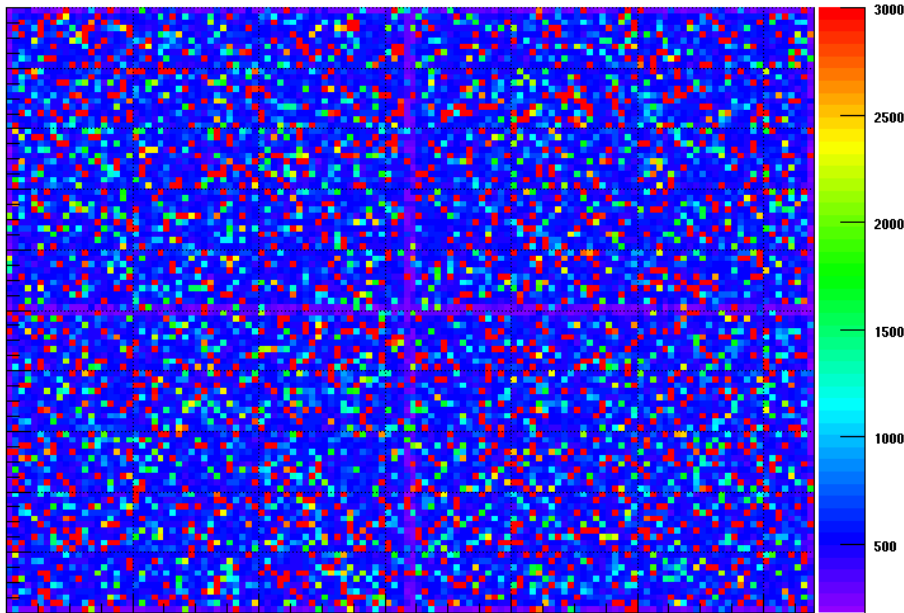


DLS 6400-22



DLS 3200-22

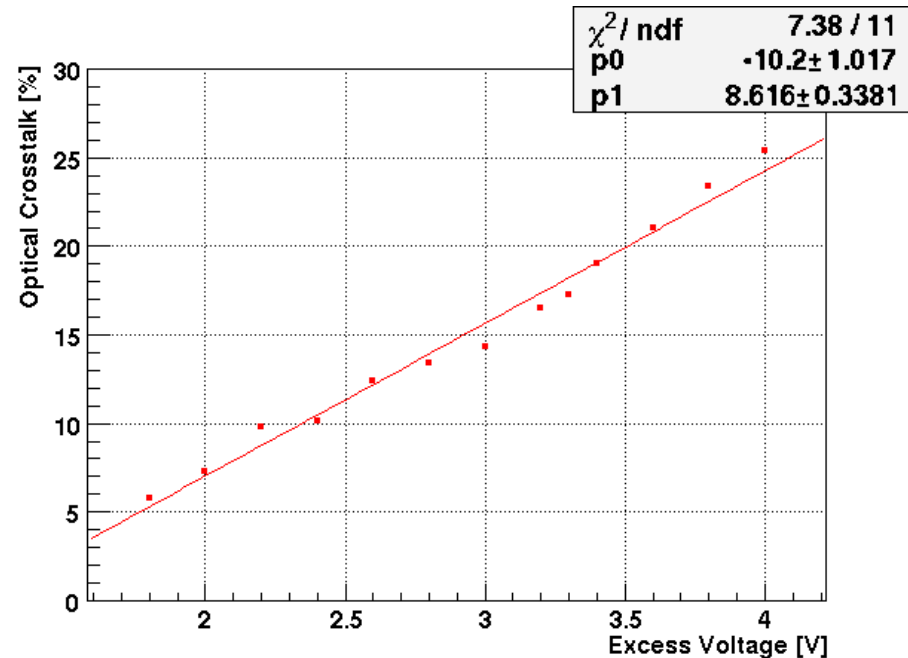
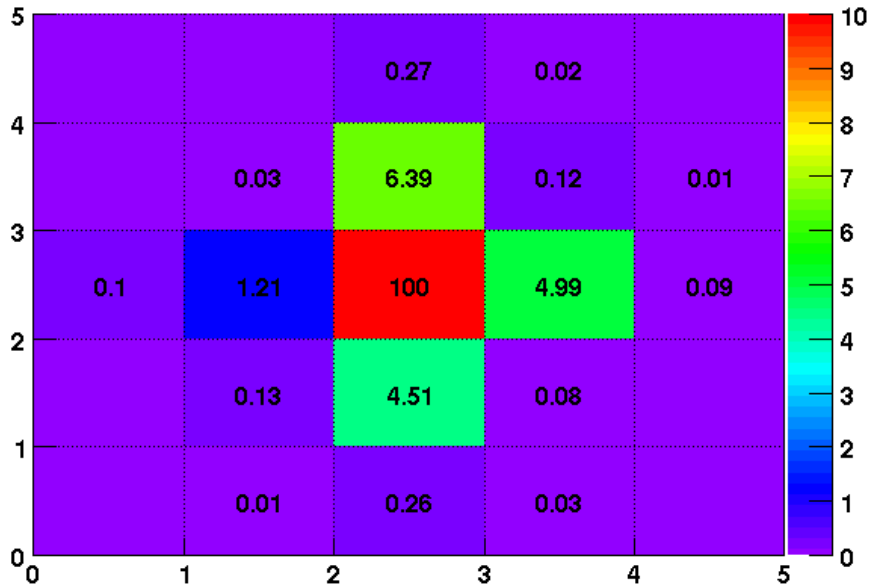
# DLS 3200-22 – Dark Count Rate



- Dark count rate at 20°C, 3.3V excess voltage
- Average dark count rate ~ 550cps per SPAD
- Scales with SPAD sensitive area (2954 $\mu\text{m}^2$  vs. 783 $\mu\text{m}^2$  in DLD8K)

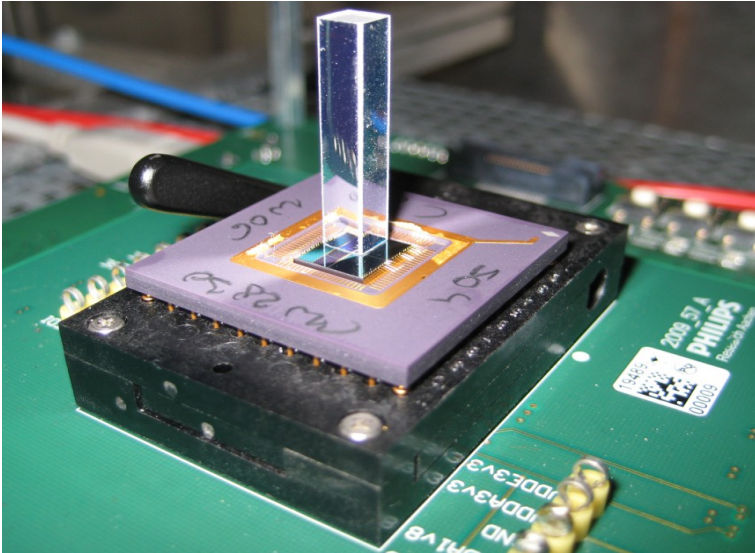
# DLS 3200-22 – Optical Crosstalk

Optical Crosstalk (%)

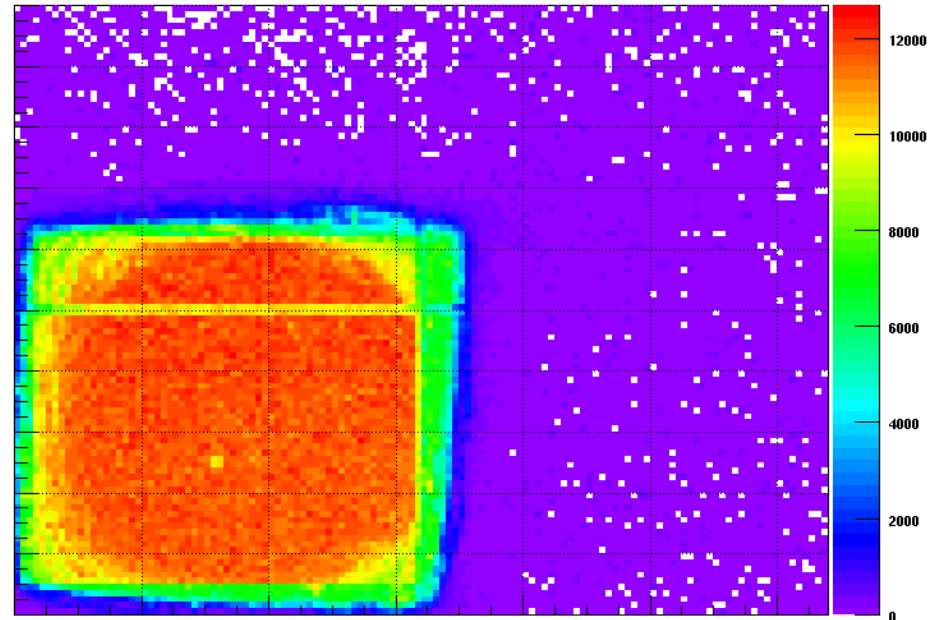


- Optical crosstalk ~18% due to higher diode capacitance (factor ~2.8)
- Linear dependence on excess voltage (as expected)
- Has to be taken into account in saturation correction

# DLS 3200-22 – Energy Resolution

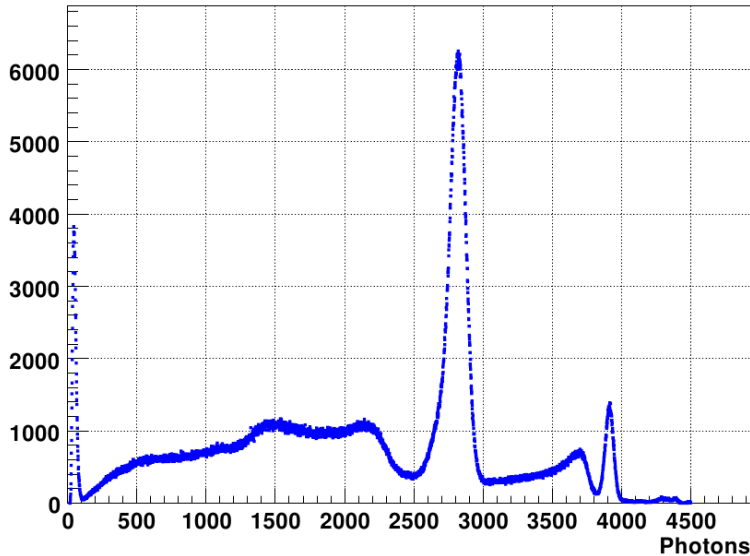


- 4 x 4 x 22 mm<sup>3</sup> LYSO crystal
- Vikuiti reflector
- Attached with Meltmount
- Na-22 source

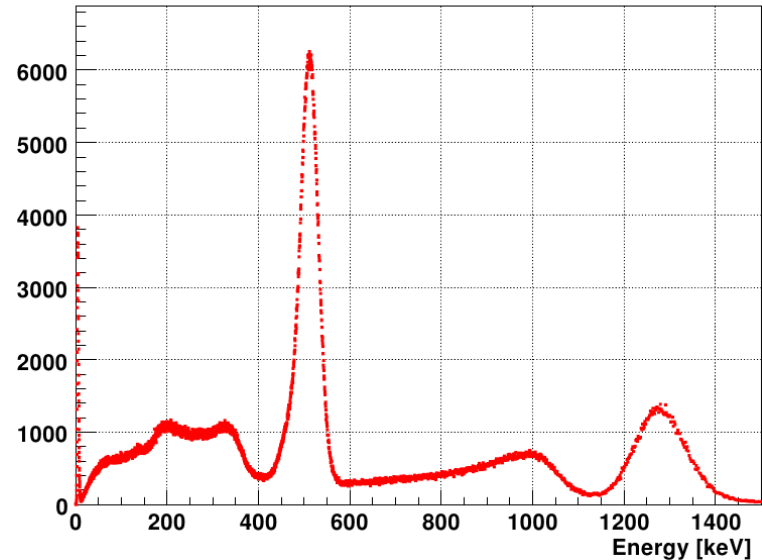


# DLS 3200-22 – Energy Resolution

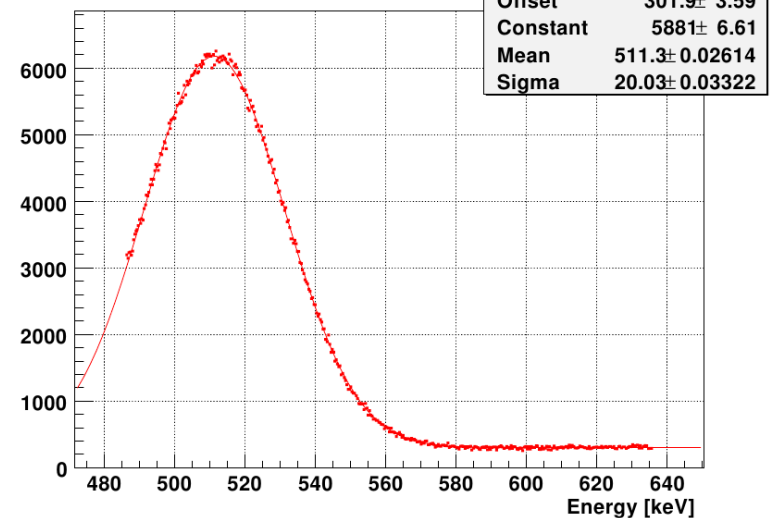
Detected Photons



Energy Spectrum



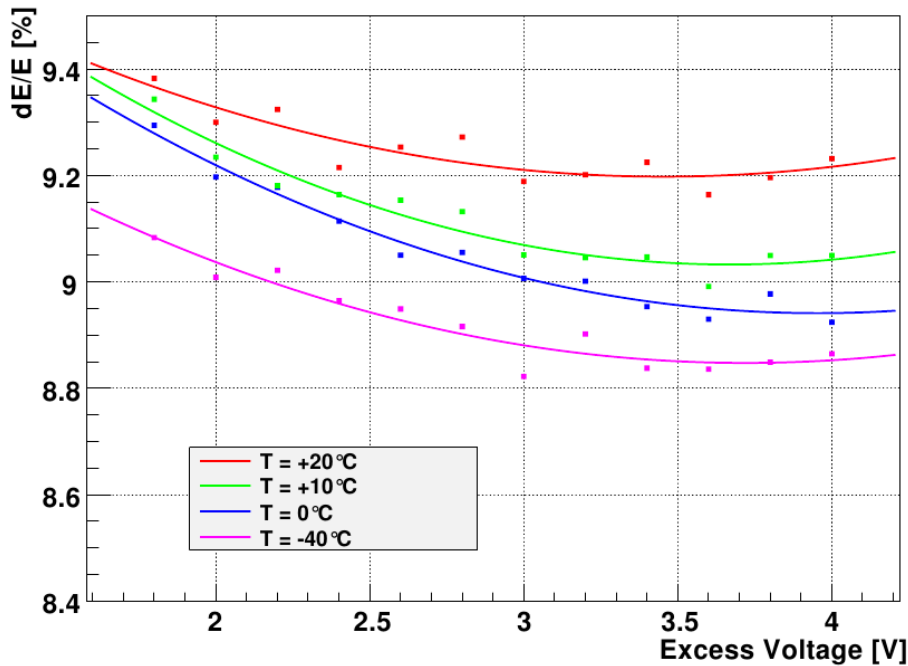
Photopeak



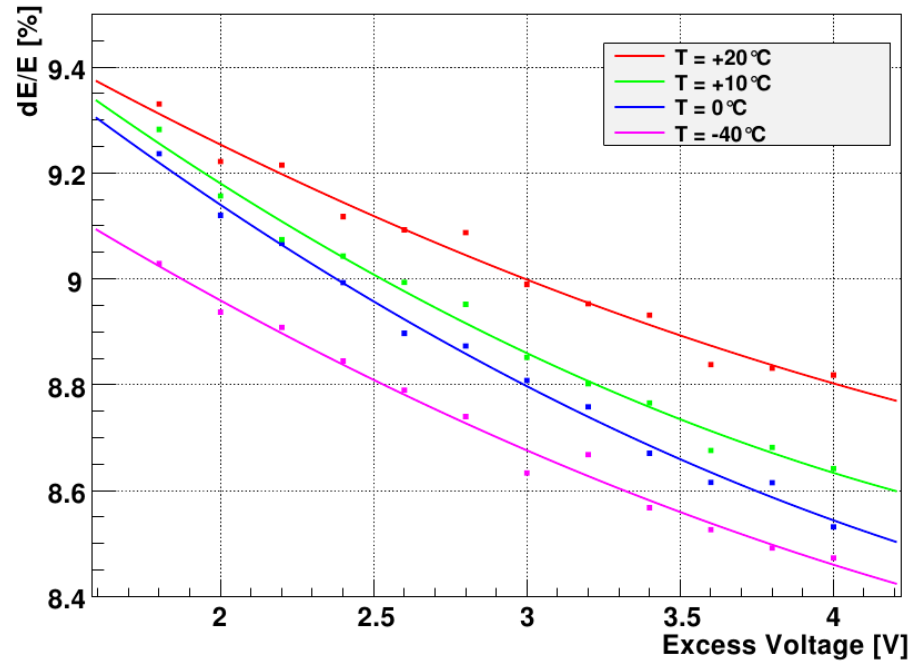
- 3.3V excess voltage, 20°C
- 99% active cells
- Non-linearity correction
- Optical crosstalk included [Burr et al.]
- $dE/E = 9.2\%$

# DLS 3200-22 – Saturation Correction

Saturation correction including optical crosstalk model [Burr et al.,2007]:



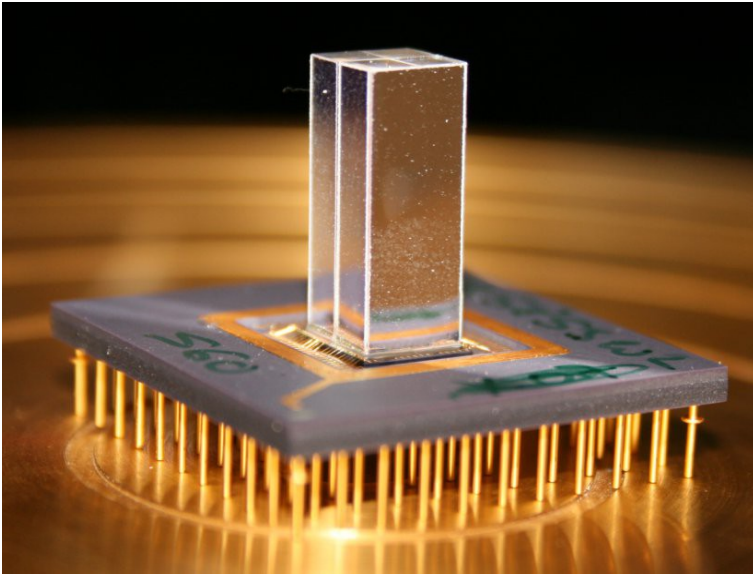
Simple saturation correction neglecting optical crosstalk:



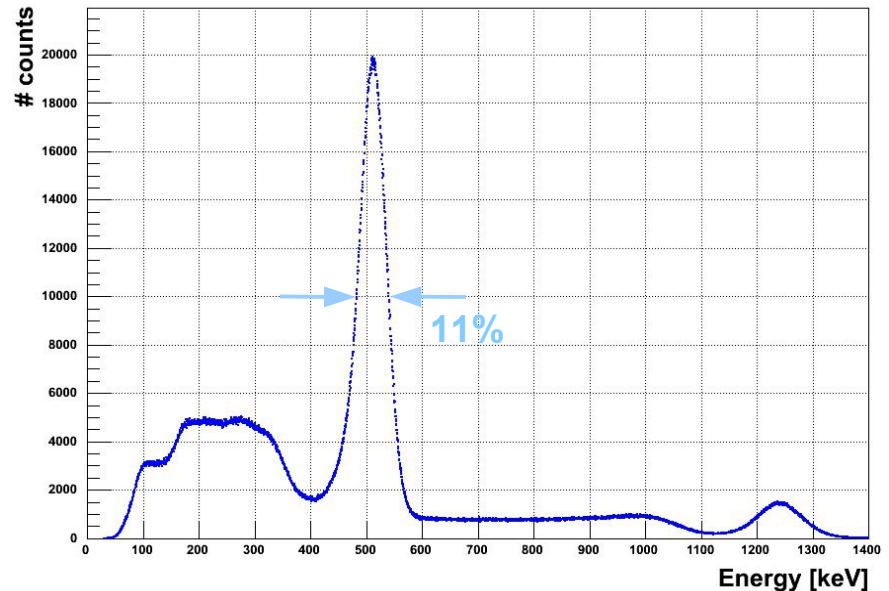
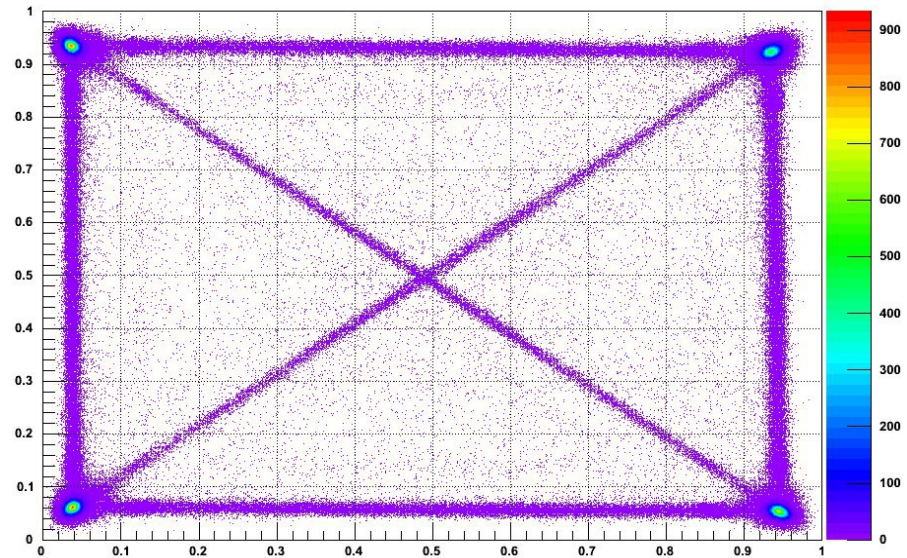
- Optical crosstalk seems to limit the energy resolution



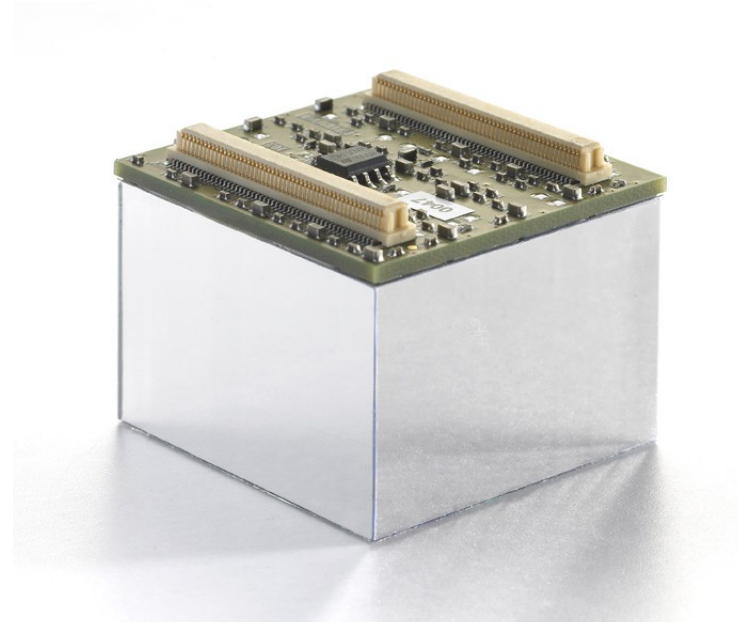
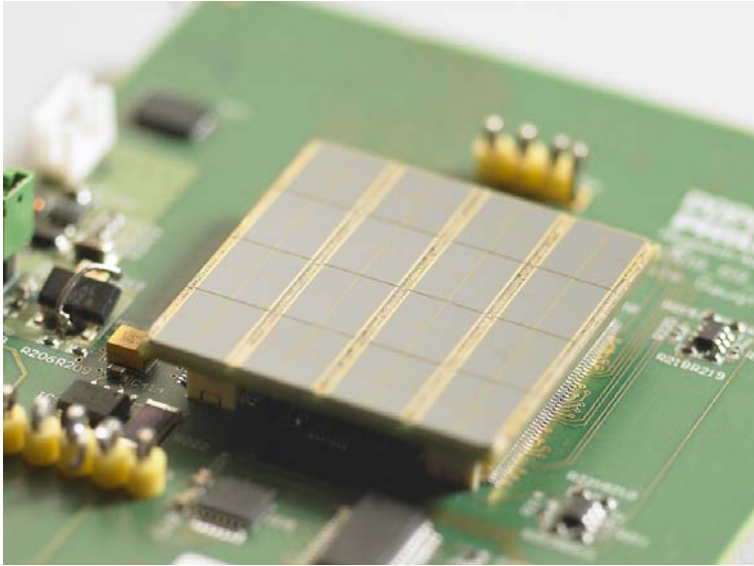
# DLS 6400-22 – Crystal Identification



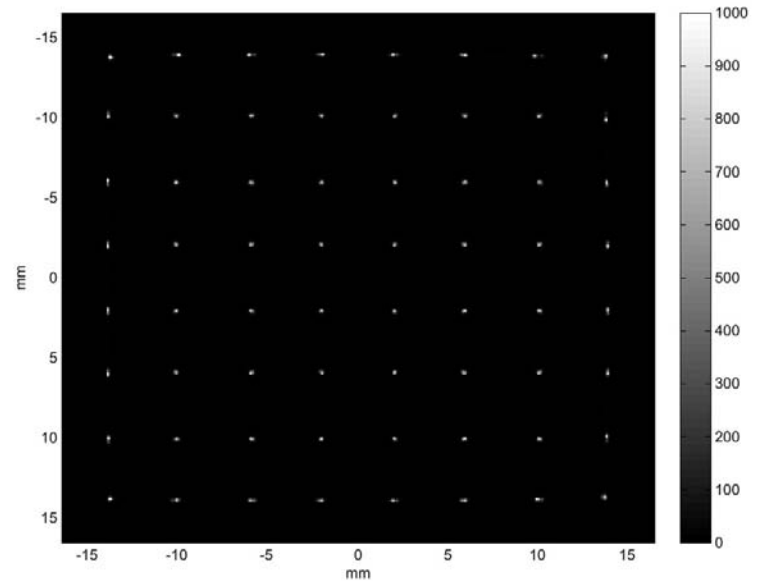
- 2x2 Array of 3x3x15mm<sup>3</sup> LYSO
- 1:1 coupling using MeltMount
- Illuminated by <sup>22</sup>Na source
- Corrected only for saturation
- dE/E = 11% (combined)



# Digital SiPM – Tiles

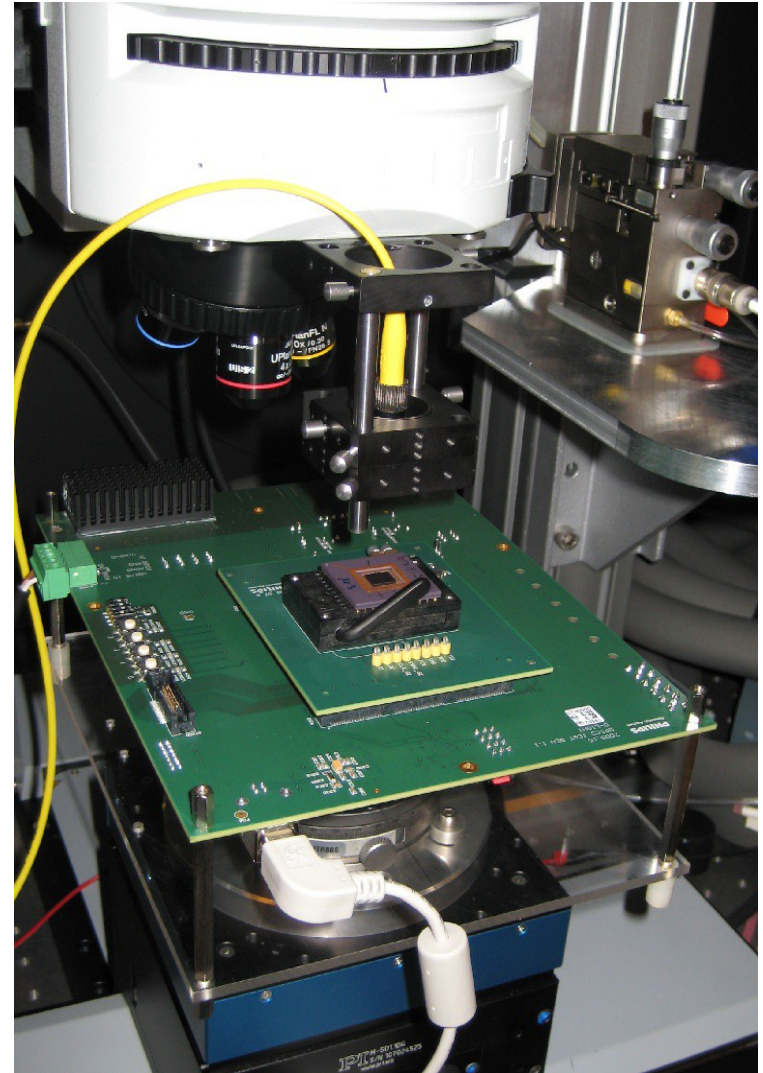
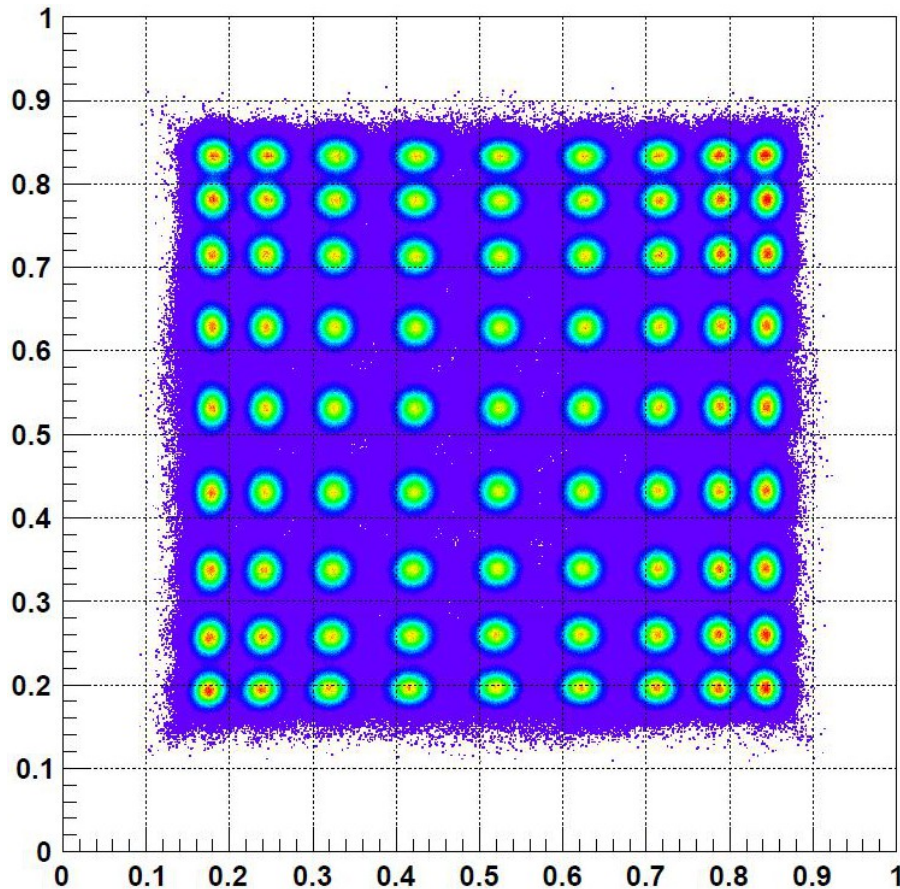


- 4 x 4 sensor array
- 8 x 8 pixels
- 4-sides tileable



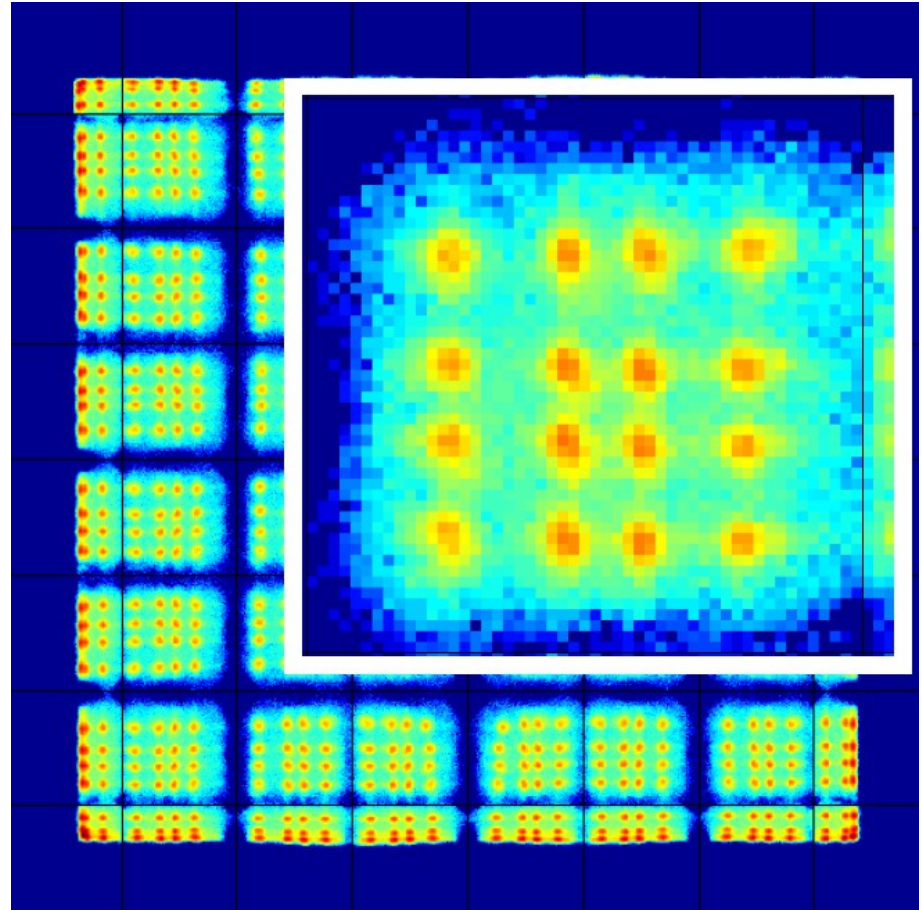
# Digital SiPM – Small Crystal Identification

- Laser measurements on a 0.5mm grid
- Best case (no scatter, no light guide)
- ~1600 photons per laser pulse



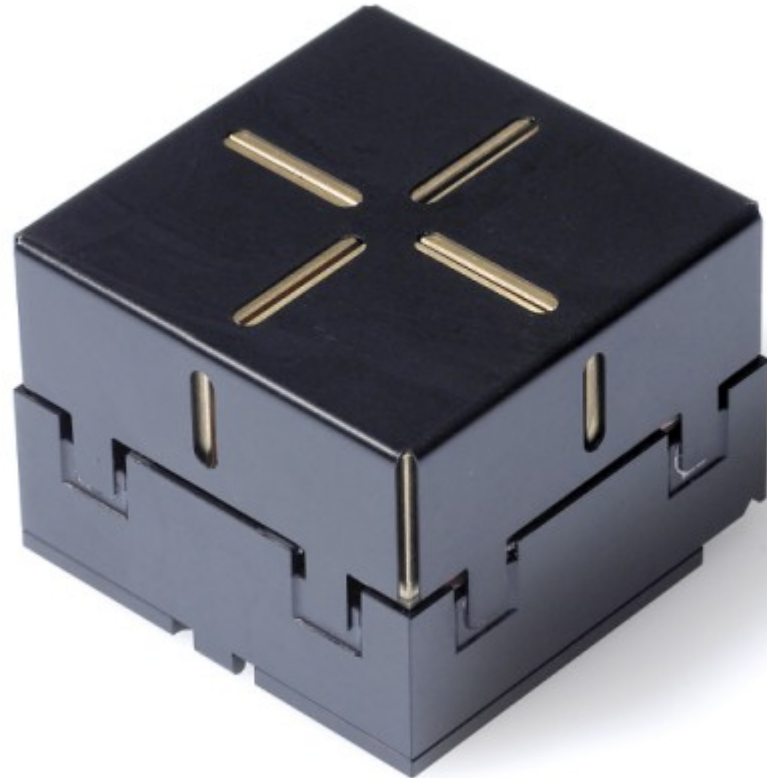
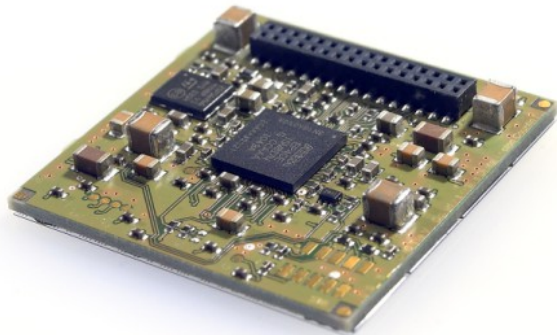
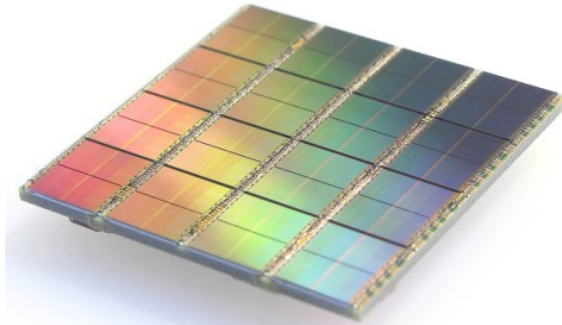
# Digital SiPM – Small Crystal Identification

- Array of 30 x 30 LYSO crystals
- Crystal size: 1 x 1 x 10mm<sup>3</sup>
- Coupled via light guide to one digital SiPM tile (4 x 4 dies)
- Data plotted in log scale
- Strong floodmap compression close to tile edge due to missing neighbor tiles



*P. Düppenbecker, Philips Research*

# DLS Tiles and Modules

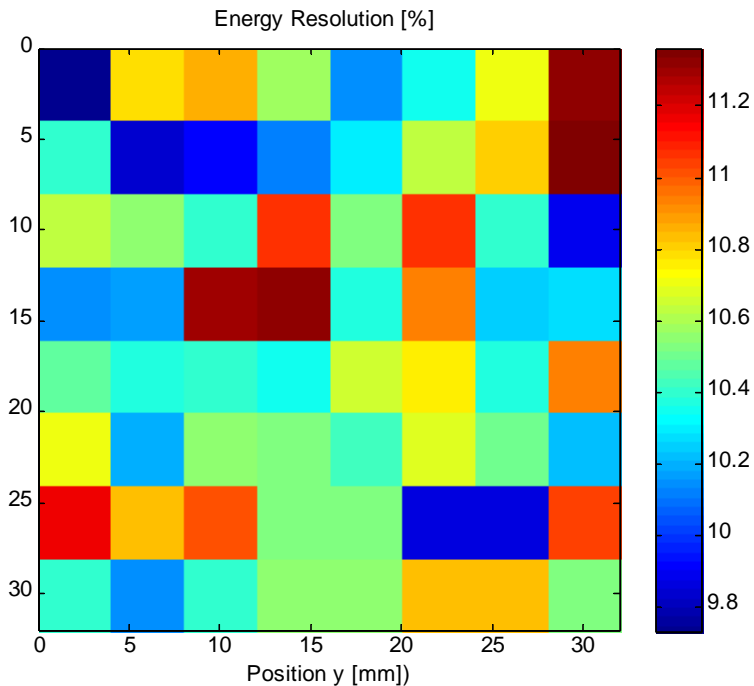


- Enables the construction of scalable detectors with large number of channels
- Power / thermal management included in design

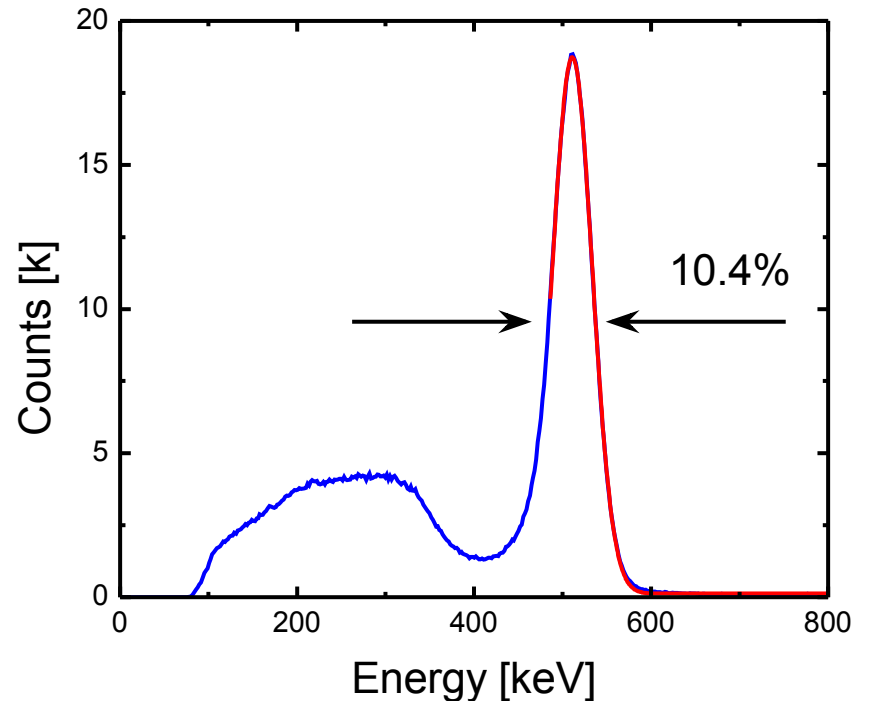
# DLS Tile – Scintillator Readout

- *LYSO array, 8 x 8 crystals, 4 mm x 4 mm pitch, 22 mm length*
- *DLS-3200-22-44, measurement at +10°C*

*Energy resolution per pixel*



*Summed histogram over all 64 pixels*

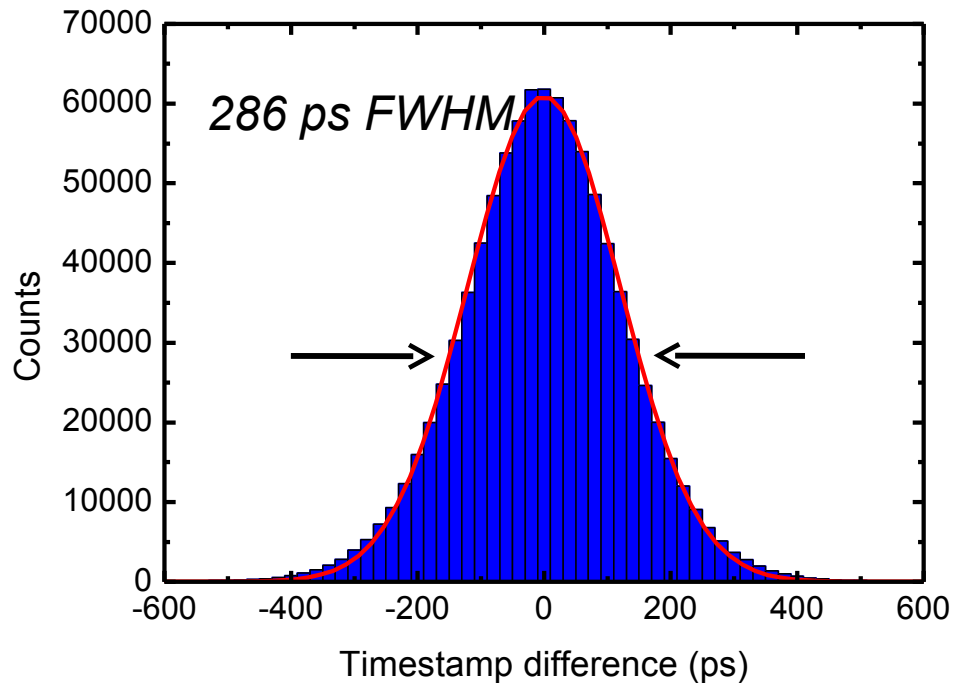


# DLS Tile – Scintillator Readout

- LYSO array, 8 x 8 crystals, 4 mm x 4 mm pitch, 22 mm length
- DLS-3200-22-44, measurement at +10°C

Timing resolution per pixel [ps]

Summed histogram over all 64 pixels



# Sensors For New Applications

- Cutting-edge experiments need high-performance sensors
  - Current sensor architecture may not fulfill all requirements
  - Ideally, the existing sensor can be extended to match the requirements but this is not always possible (different requirements on cell/chip size)
  - Dedicated designs needed but require large NRE investment per design
- Dedicated SiPMs, different cell and die sizes, analog or digital data processing
  - Vanishing boundary between photon detection and data processing
  - Early user feedback and application knowledge crucial for development
    - allow the users to develop their own dedicated digital SiPMs
- **Philips/NXP plan to offer multi-project wafer runs to the HEP community**
  - Many experienced designers already working on mixed-signal ROCs
  - Develop your own digital SiPM sensors tailored to your experiment
  - Share the experience and mask cost with other users
  - Is there sufficient demand for multi-project wafer service in this technology?

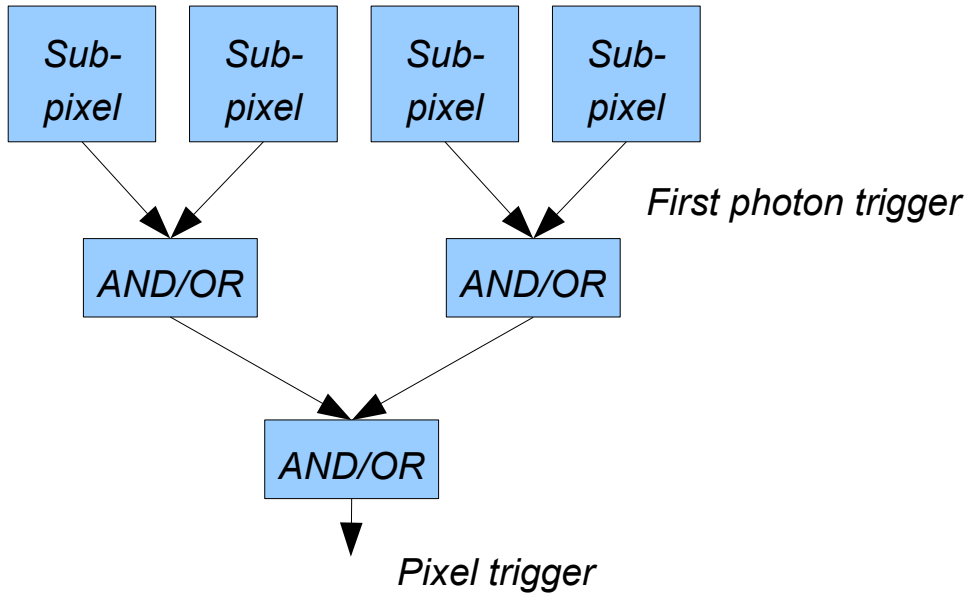


# Summary

- Digital SiPM implemented in a high-volume CMOS process
- Configurable architecture, individual control of each SPAD
- Tiles of 4 x 4 sensors and modules with 2 x 2 tiles developed
- New design with improved fill factor of 78% currently being tested
  
- Multi-project wafer runs planned to allow users to develop application specific sensors. Please contact us if you are interested.

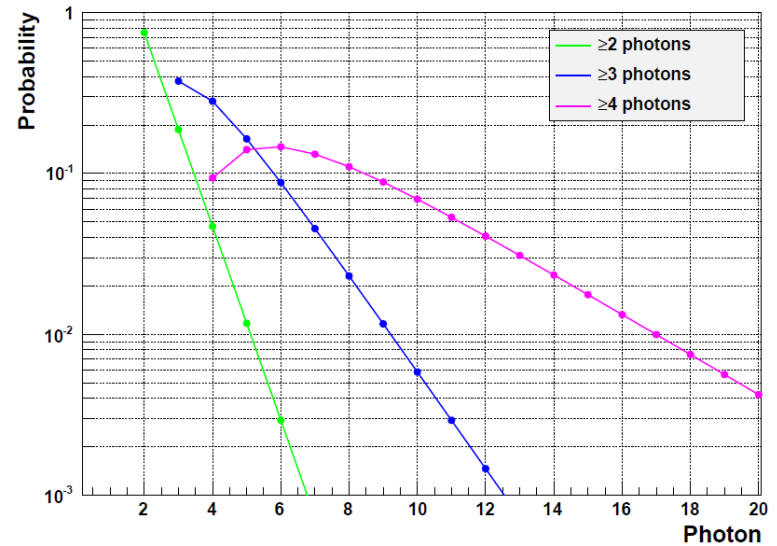


# Digital SiPM – Trigger Logic

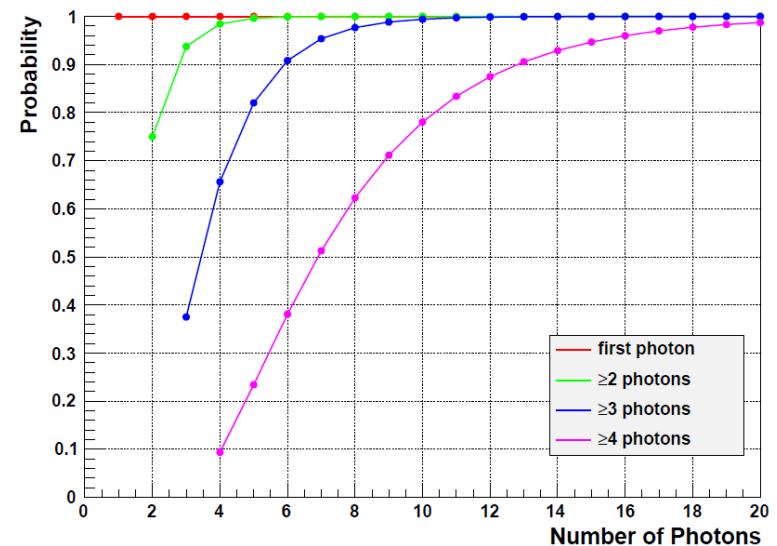


- Each sub-pixel triggers at first photon
- Sub-pixel trigger can be OR-ed or AND-ed to generate probabilistic trigger thresholds
- Higher trigger threshold decreases system dead-time at high dark count rates at the cost of time resolution

Trigger Probability per Photon

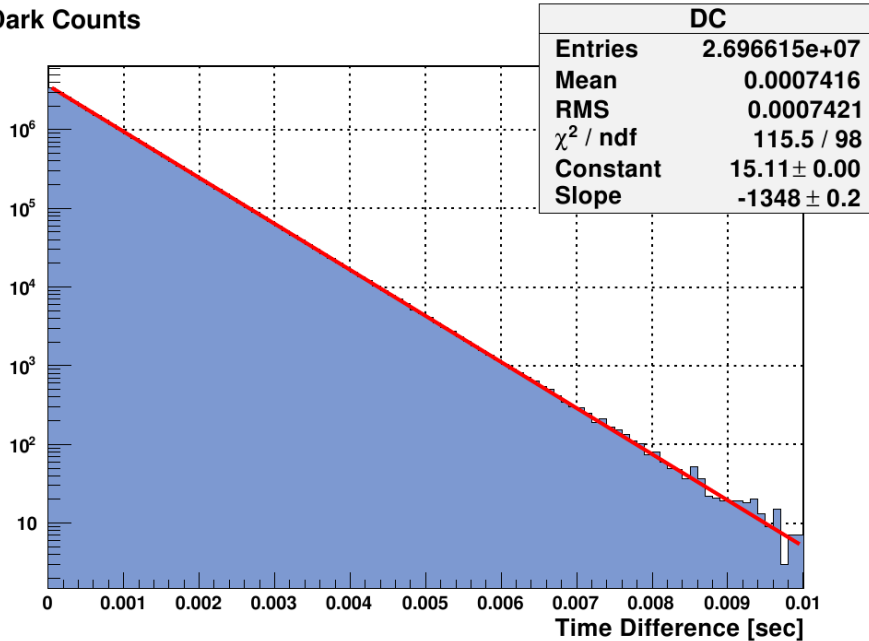


Cumulative Trigger Probability

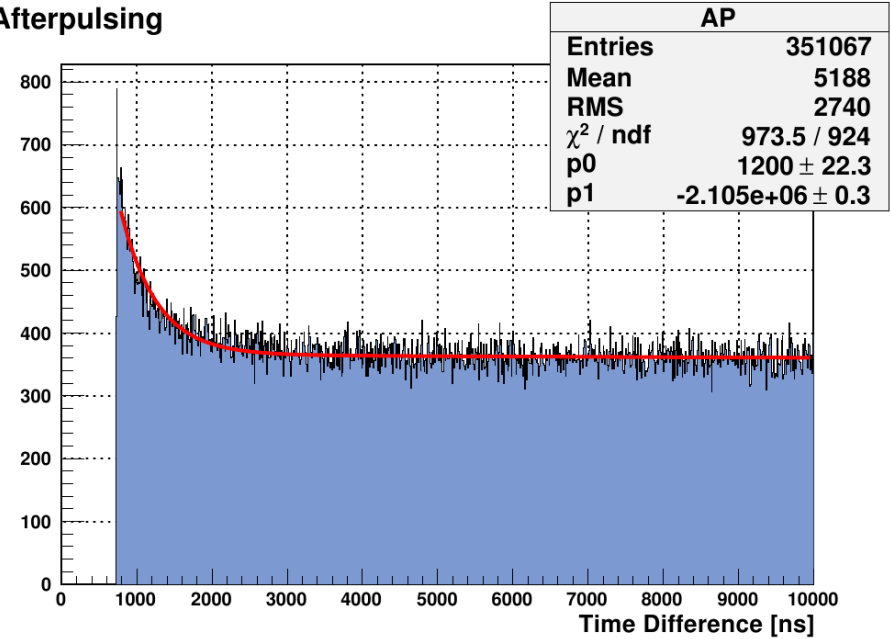


# Digital SiPM – Afterpulsing Probability

Dark Counts



Afterpulsing



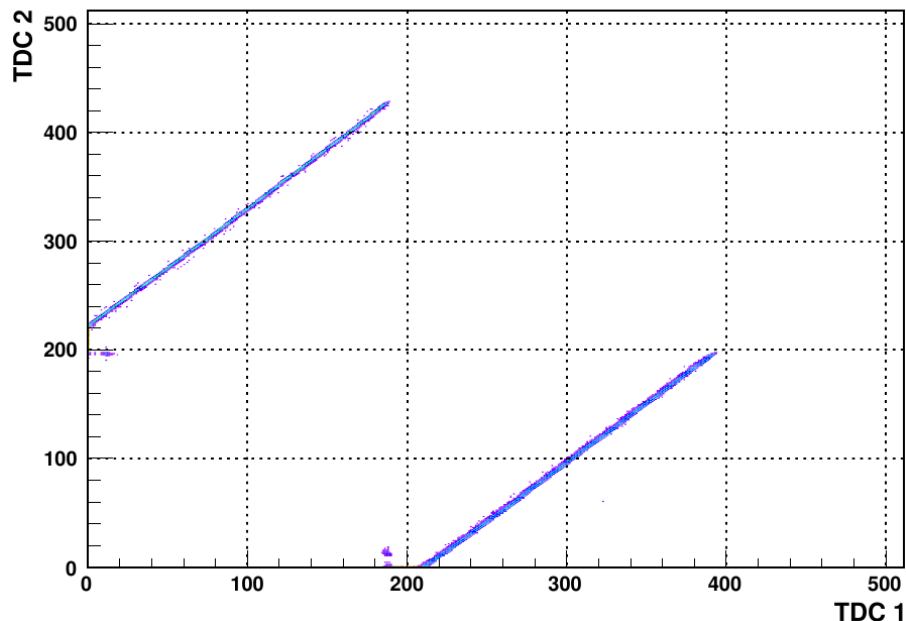
Time differences of two consecutive dark counts in a single diode.

Afterpulsing: deviation from the Poisson distribution in the first few  $\mu\text{s}$ .

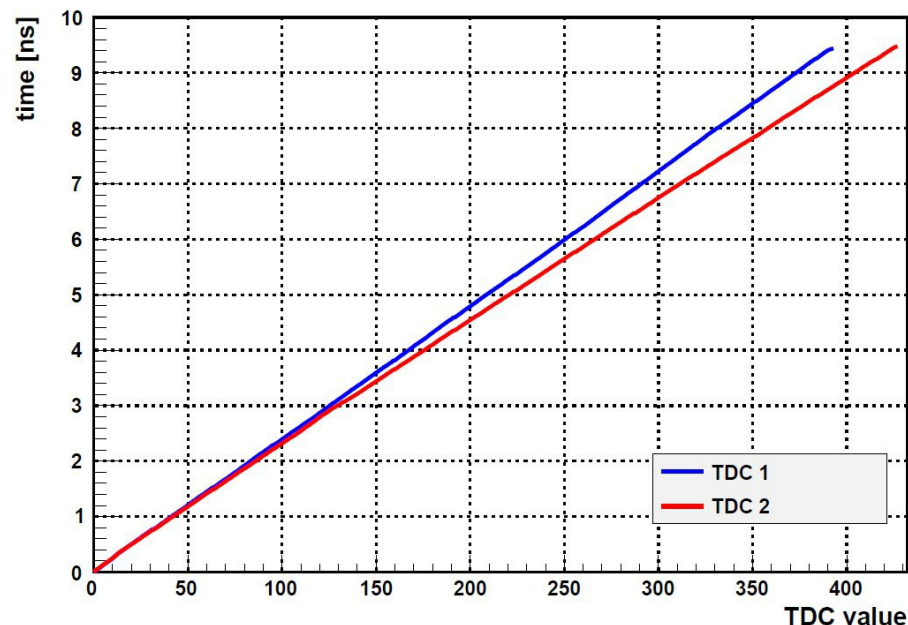
Many diodes show afterpulsing probabilities of less than 0.1%, few are in the 2-3% range.

# Digital SiPM – Time-to-Digital Converter

TDC Correlation



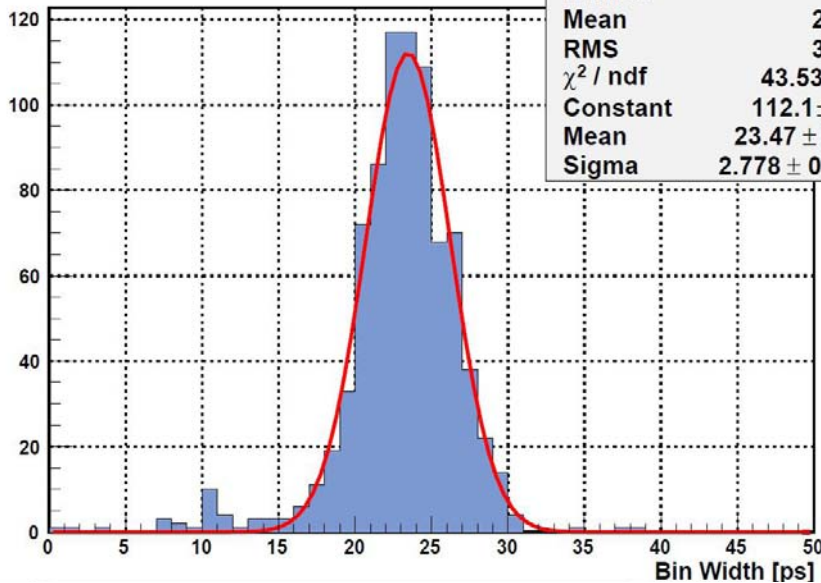
TDC Linearity



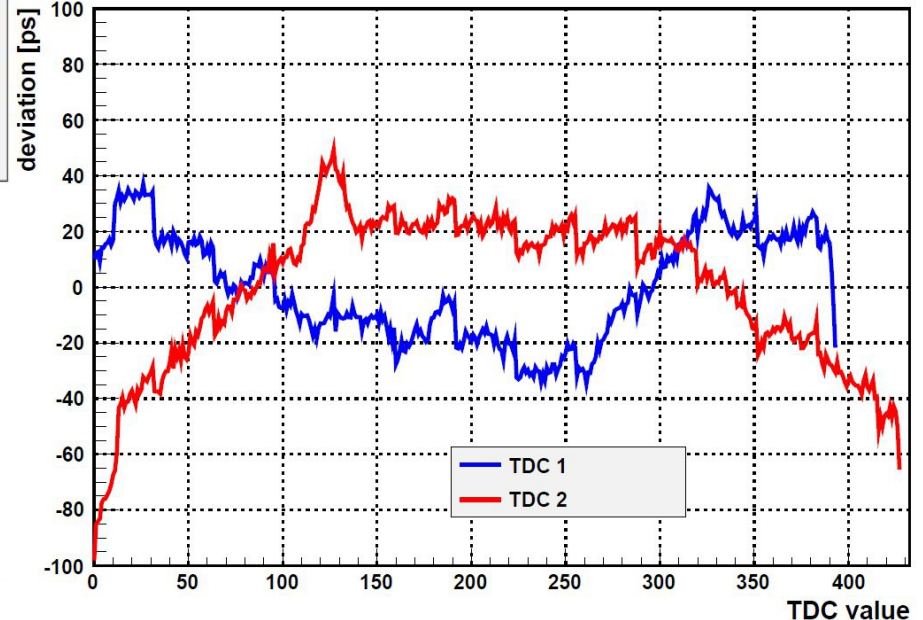
- Two identical 9 bit TDCs running with 180° phase-shifted clocks
- 100MHz reference clock generated from 200MHz system clock
- Each TDC has ~0.5ns wide 'blind spot' close to clock edge → bin 0
- Two-phase clock guarantees at least one valid TDC value for any event
- For ~90% of the events, both TDC values can be used to increase accuracy
- TDC calibration using dark counts or randomly distributed events

# Digital SiPM – Time-to-Digital Converter

Bin Width Histogram



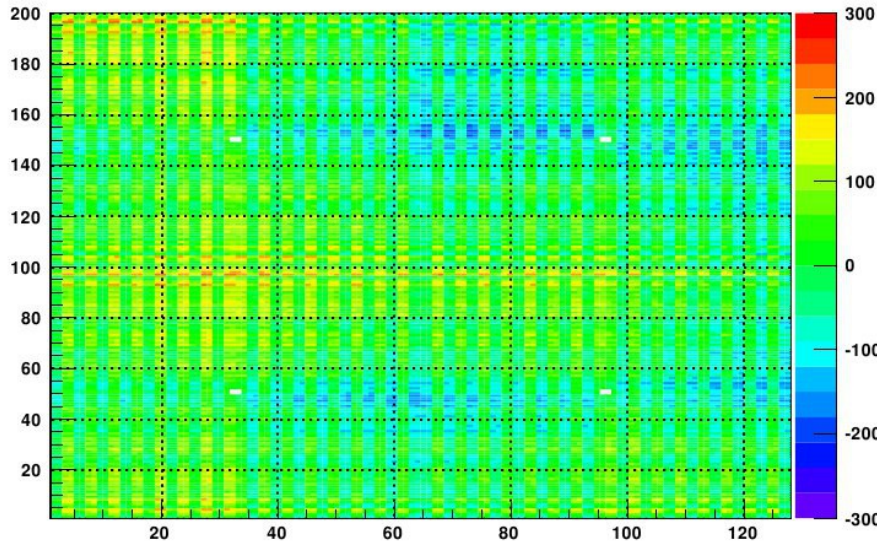
TDC Non-Linearity



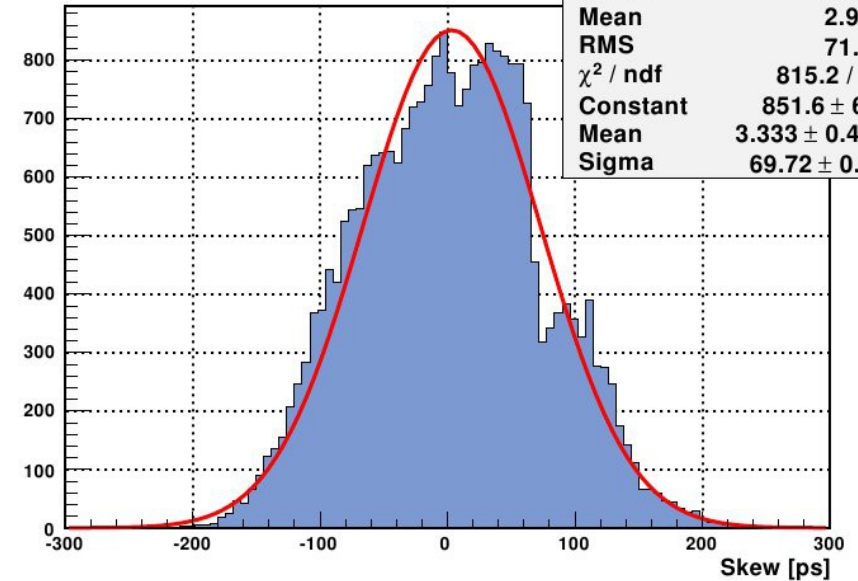
- Average TDC bin width  $23 \pm 2.8\text{ps}$
- Non-linearity corrected by look-up tables inside the readout FPGA
- Online correction for TDC drift due to temperature and voltage variation
- Periodic TDC calibration test using external (SYNC) signal

# Digital SiPM – Trigger Network Skew

Trigger Network Skew



Trigger Network Skew Histogram



- Chip illuminated by divergent picosecond laser beam
- Laser trigger synchronized to the reference clock
- All diodes measured sequentially
- 10000 events captured and time stamp histogram fitted with a Gaussian
- Gaussian mean  $\rightarrow$  delay of the selected trigger path
- Average trigger network delay subtracted from the data